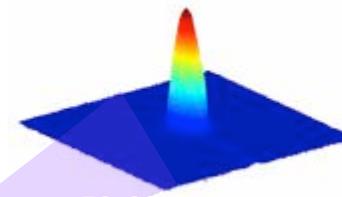
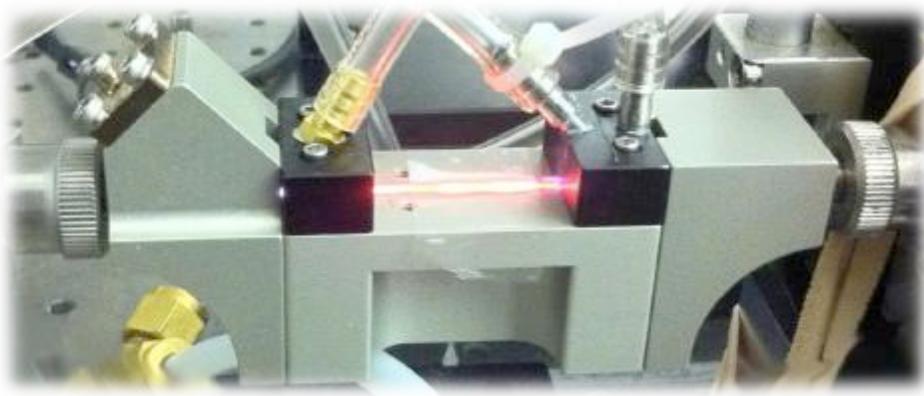
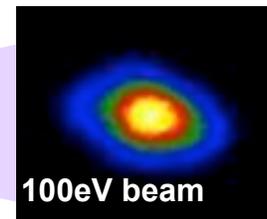
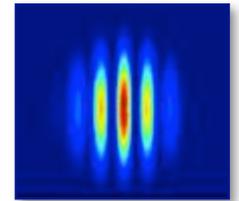


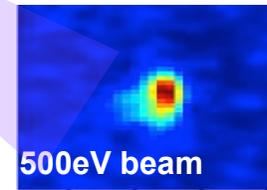
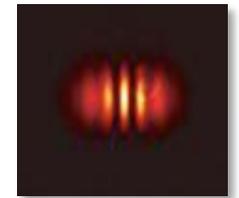
Nanoscale Materials Metrology using Coherent EUV High Harmonic Beams



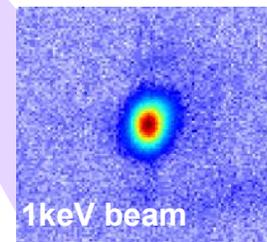
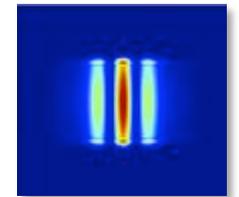
50eV beam



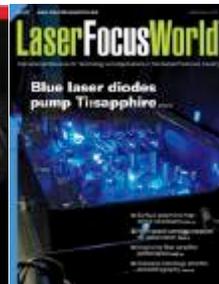
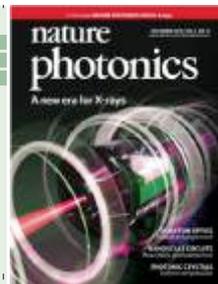
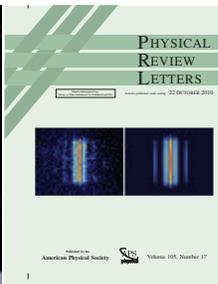
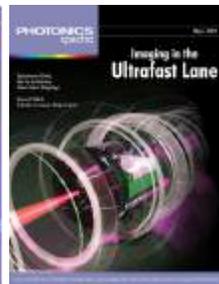
100eV beam



500eV beam

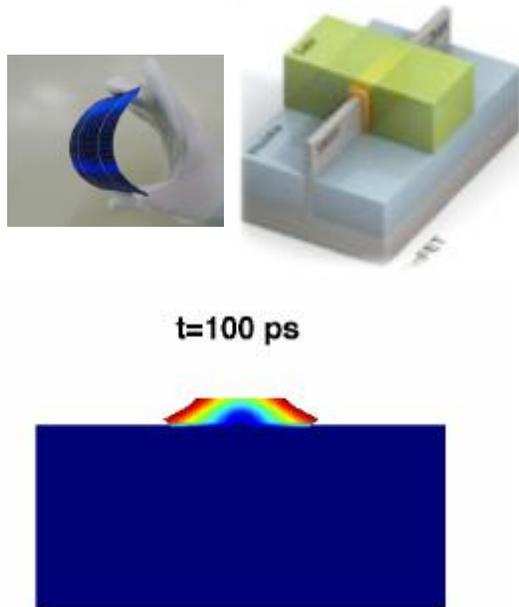


1keV beam

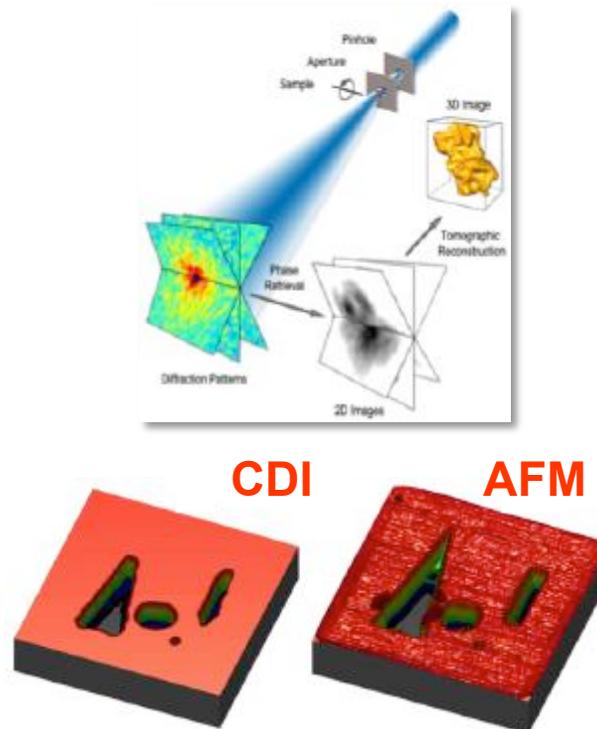


Nanoscale Materials Metrology using Coherent EUV High Harmonic Beams

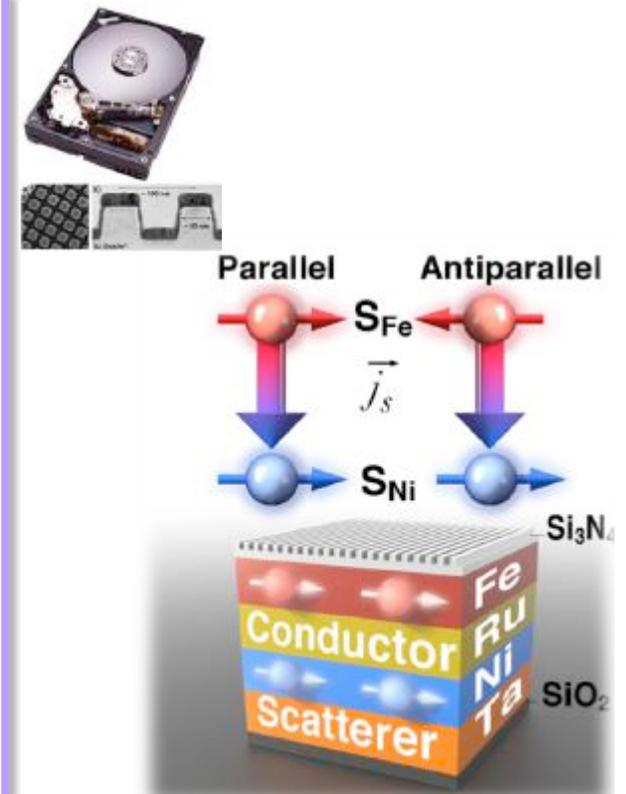
Acoustic nanometrology



Nanoscale coherent imaging

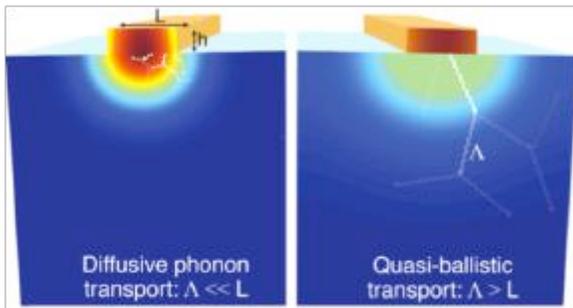
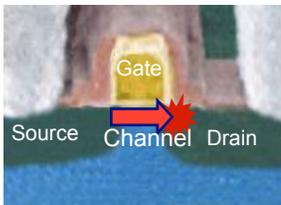


Nanoscale spintronics

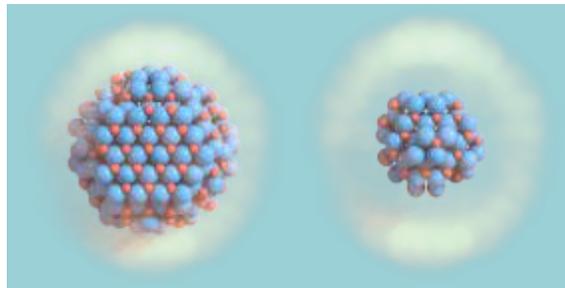
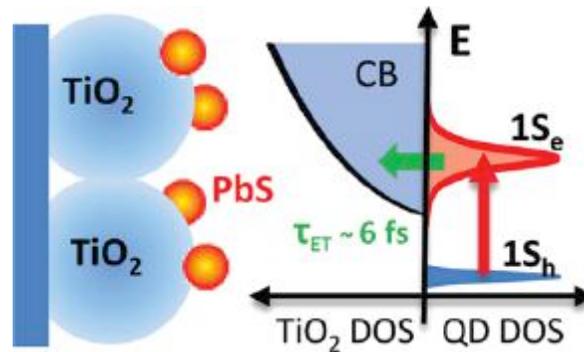


Nanoscale Materials Metrology using Coherent EUV High Harmonic Beams

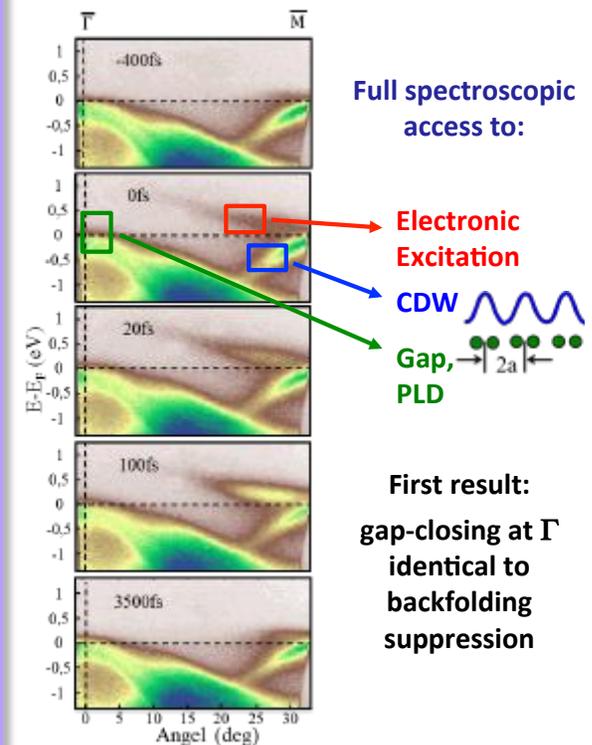
Nanoscale heat flow



Photoemission quantum dots



Photoemission solids



Tenio Popmintchev, Ming-Chang Chen, Damiano Nardi, Kathy Hoogeboom-Pot, Jorge Hernandez-Charpak, Chan La-O-Vorakiat, Emrah Turgut, Dan Adams, Matt Seaberg, Dennis Gardener, Margaret Murnane, Henry Kapteyn
JILA, University of Colorado at Boulder

Andrius Baltuška
Technical University Vienna

Eric Anderson, Eric Gullikson, Yanwei Liu, Farhad Salmassi
LBL

Marie Tripp and Sean King
Intel

Bruce Gurney, Olav Hellwig
Hitachi

Stefan Mathias, Martin Aeschlimann, Claus Schneider
Kaiserslautern and Jülich

Tom Silva, Justin Shaw, Hans Nembach
NIST

Carmen Menoni
CSU

Bill Schlotter
SLAC



Colorado **JILA**
University of Colorado at Boulder **NIST/UCO**

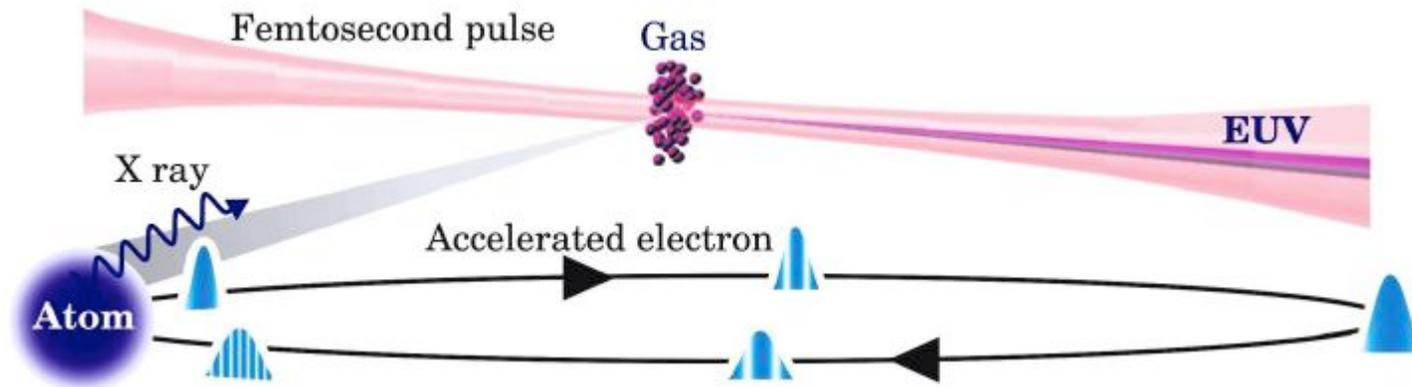


TECHNISCHE UNIVERSITÄT
KAISERSLAUTERN

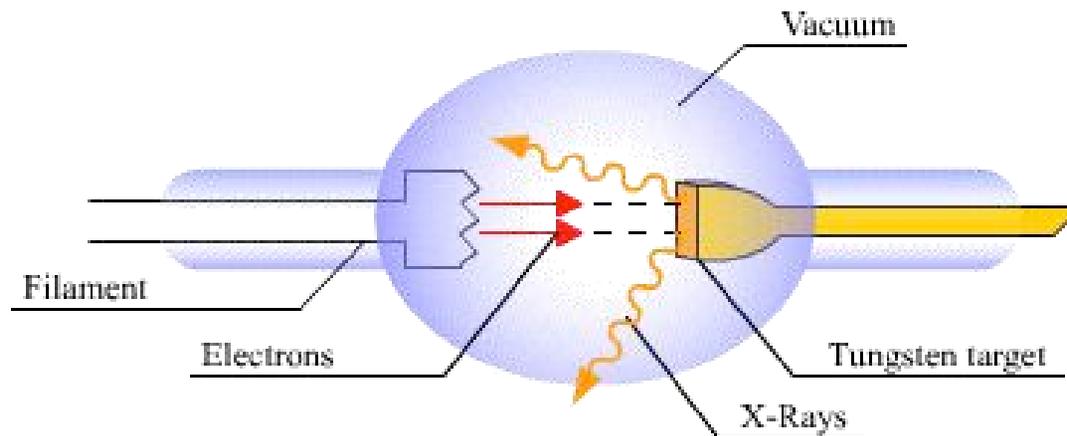


NSSEFF

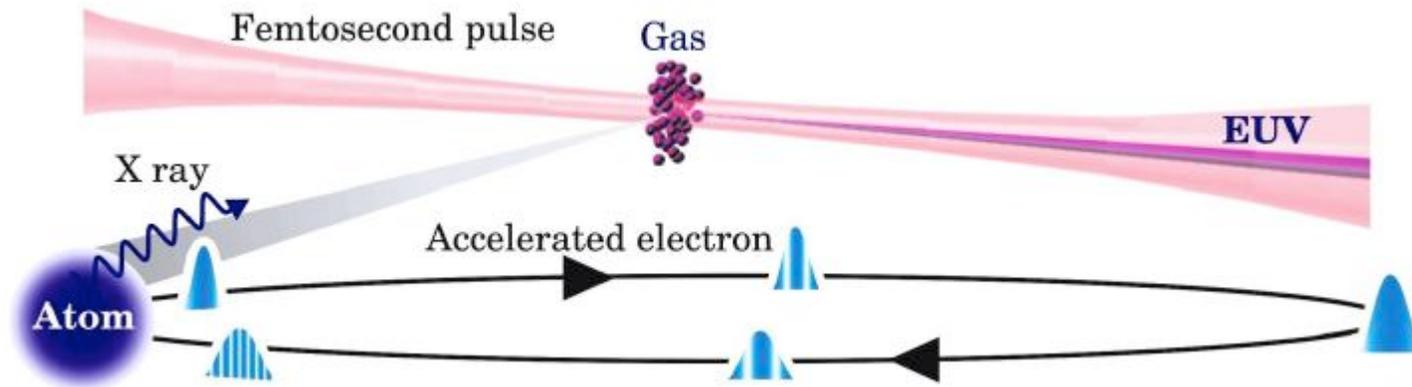
National Security Science and Engineering
Faculty Fellowship Competition



High Harmonic Generation



Röntgen X-ray Tube



High Harmonic Generation

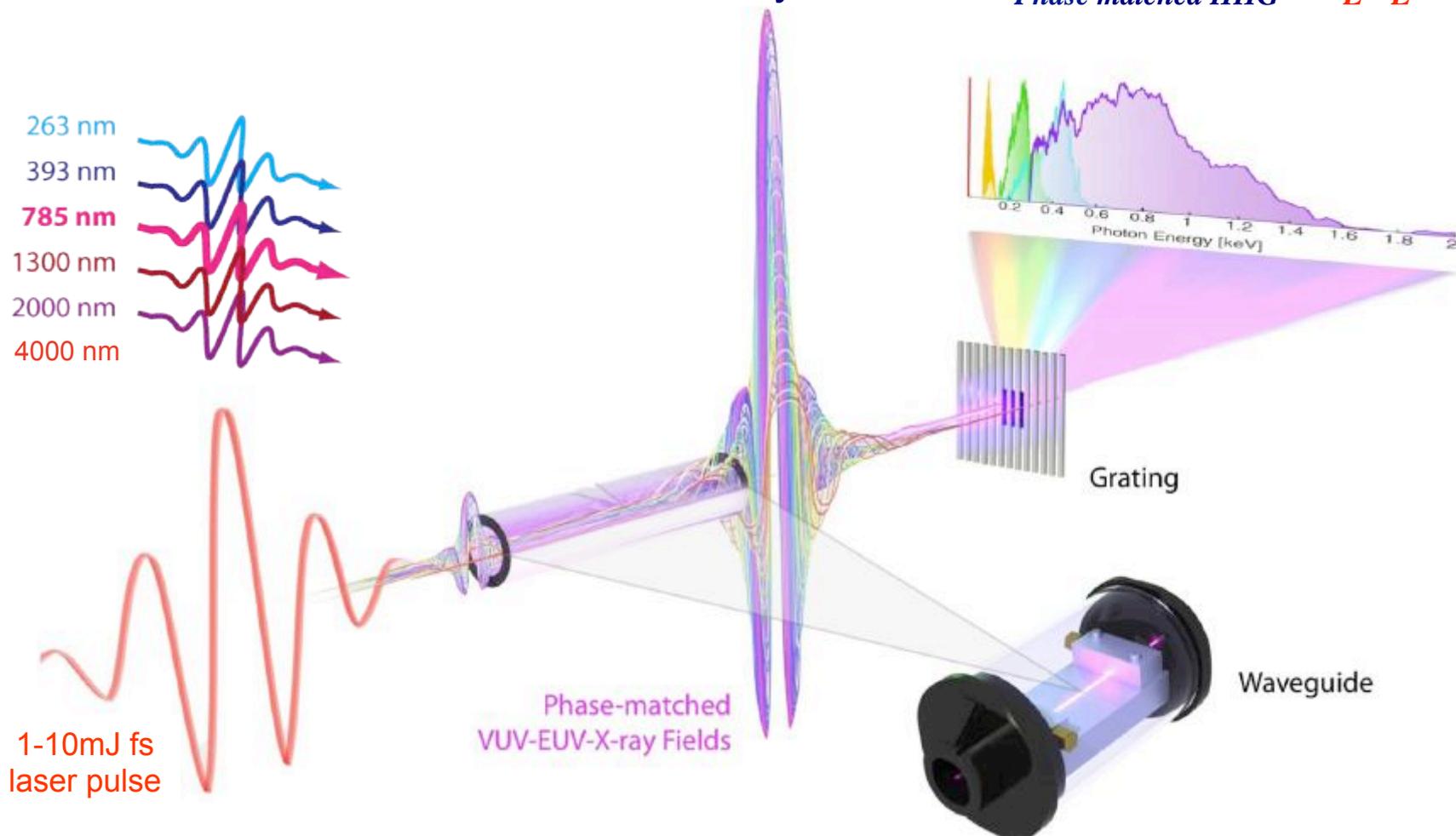


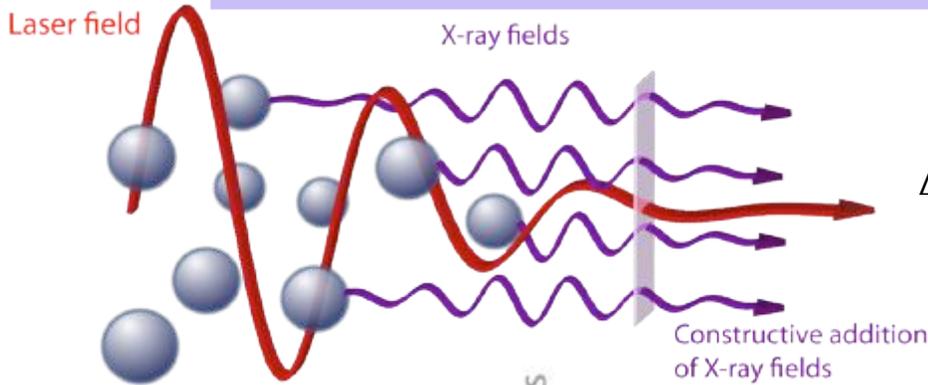
Extreme nonlinear optics

What driving laser wavelength and gas pressure to use for bright HHG?

1. Need bright single atom emission: $h\nu_{\text{Single atom HHG}} \propto I_L \lambda_L^2$

2. Need coherent addition from many atoms: $h\nu_{\text{Phase matched HHG}} \propto I_L \lambda_L^{1.7}$

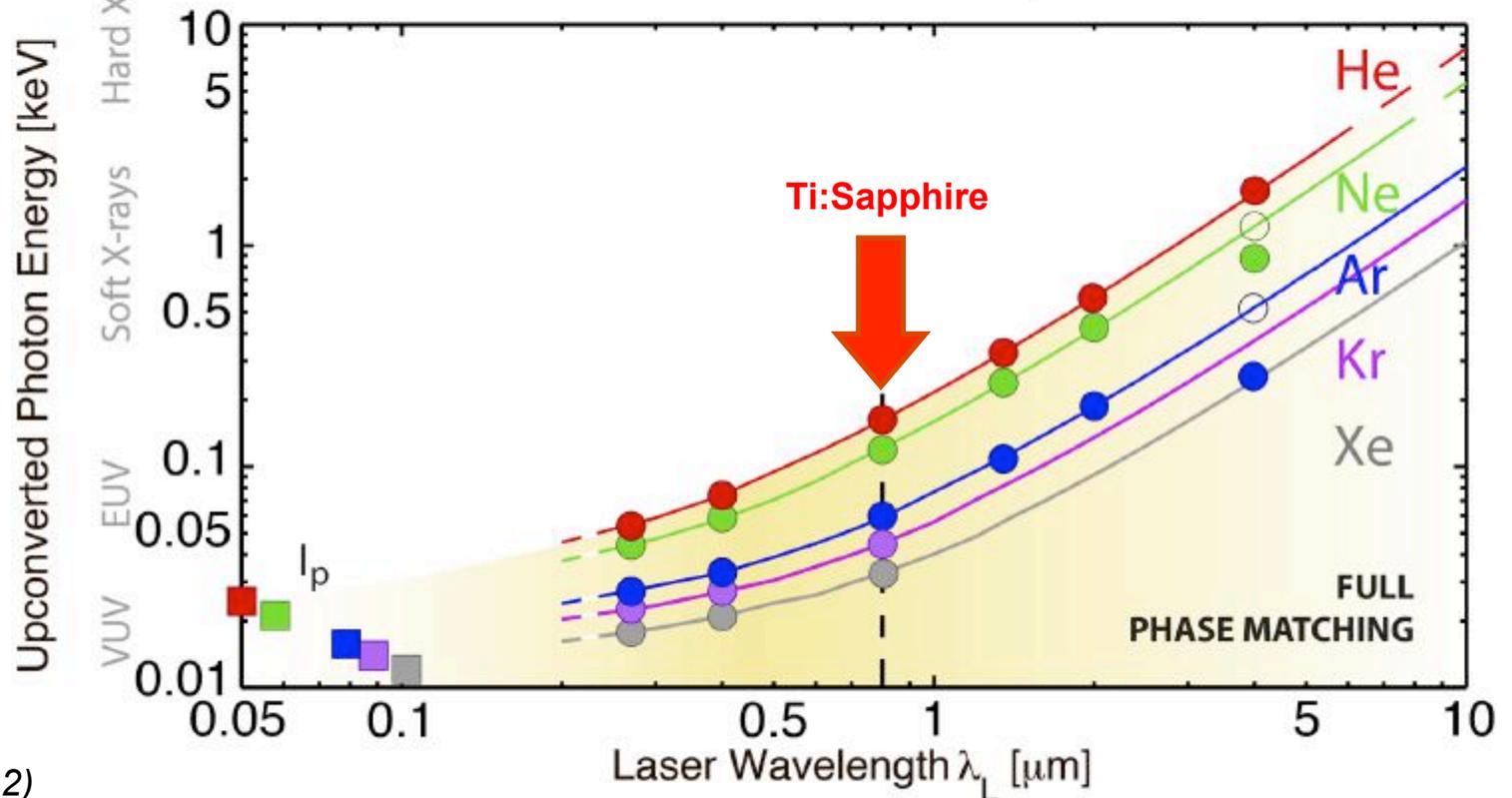


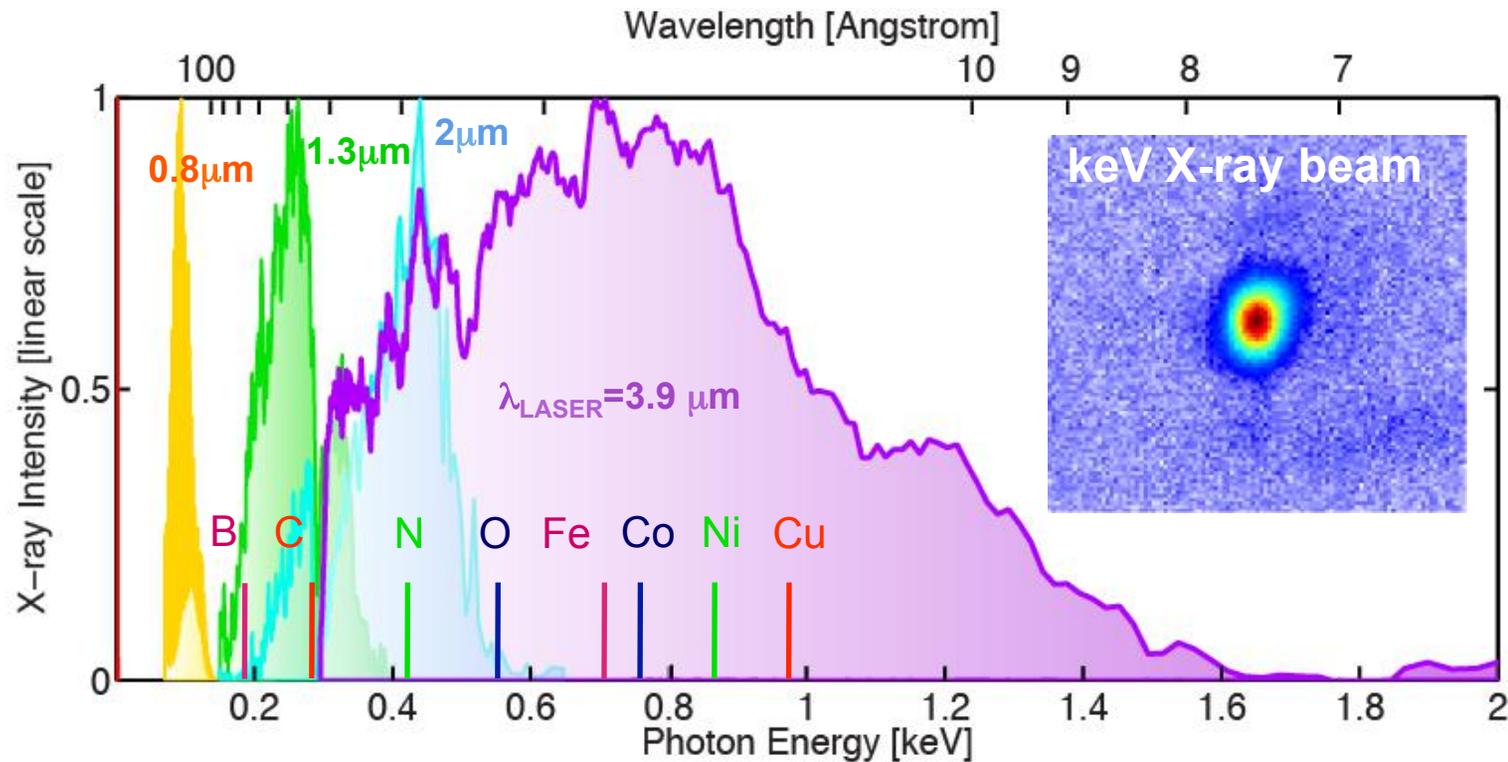


$$\Delta k = q \left\{ \left(\frac{u_{11}^2 \lambda_0}{4\pi a^2} \right) - P \left((1 - \eta) \frac{2\pi}{\lambda_0} \Delta\delta - \eta [N_{atm} r_e \lambda_0] \right) \right\}$$

Phase Matching Cutoffs
VUV-EUV-Soft & Hard X-rays

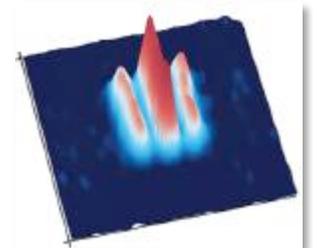
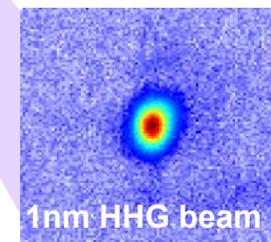
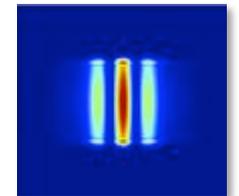
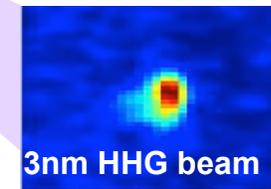
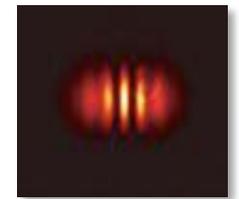
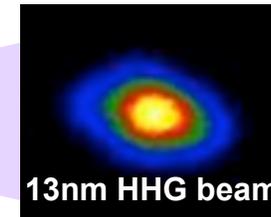
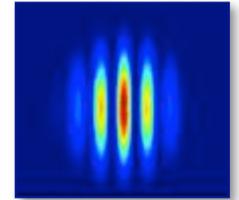
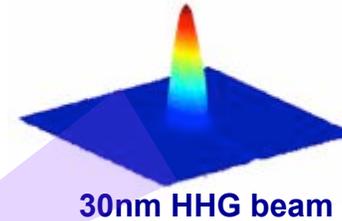
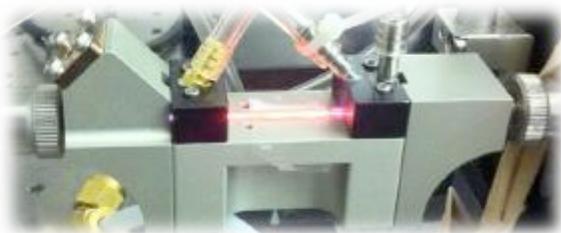
- For **keV** HHG, need mid IR lasers
- For **EUV** HHG, want 0.8 μ m lasers
- For **VUV** HHG, want UV lasers





- Bright coherent tabletop keV X-rays for first time
- Highest nonlinear and phase matched process at > 5000 orders
- Phase matching bandwidth ultrabroad since $v_{\text{X-rays}} \approx c$
- Coherent spectrum spans many elemental x-ray edges

263 nm
393 nm
785 nm
1300 nm
2000 nm
4000 nm



Current conversion efficiency:

10-50 eV: $10^{-3} - 10^{-4}/\text{eV}$ (per 1% band)

50-100 eV: $10^{-5} - 10^{-6} /\text{eV}$

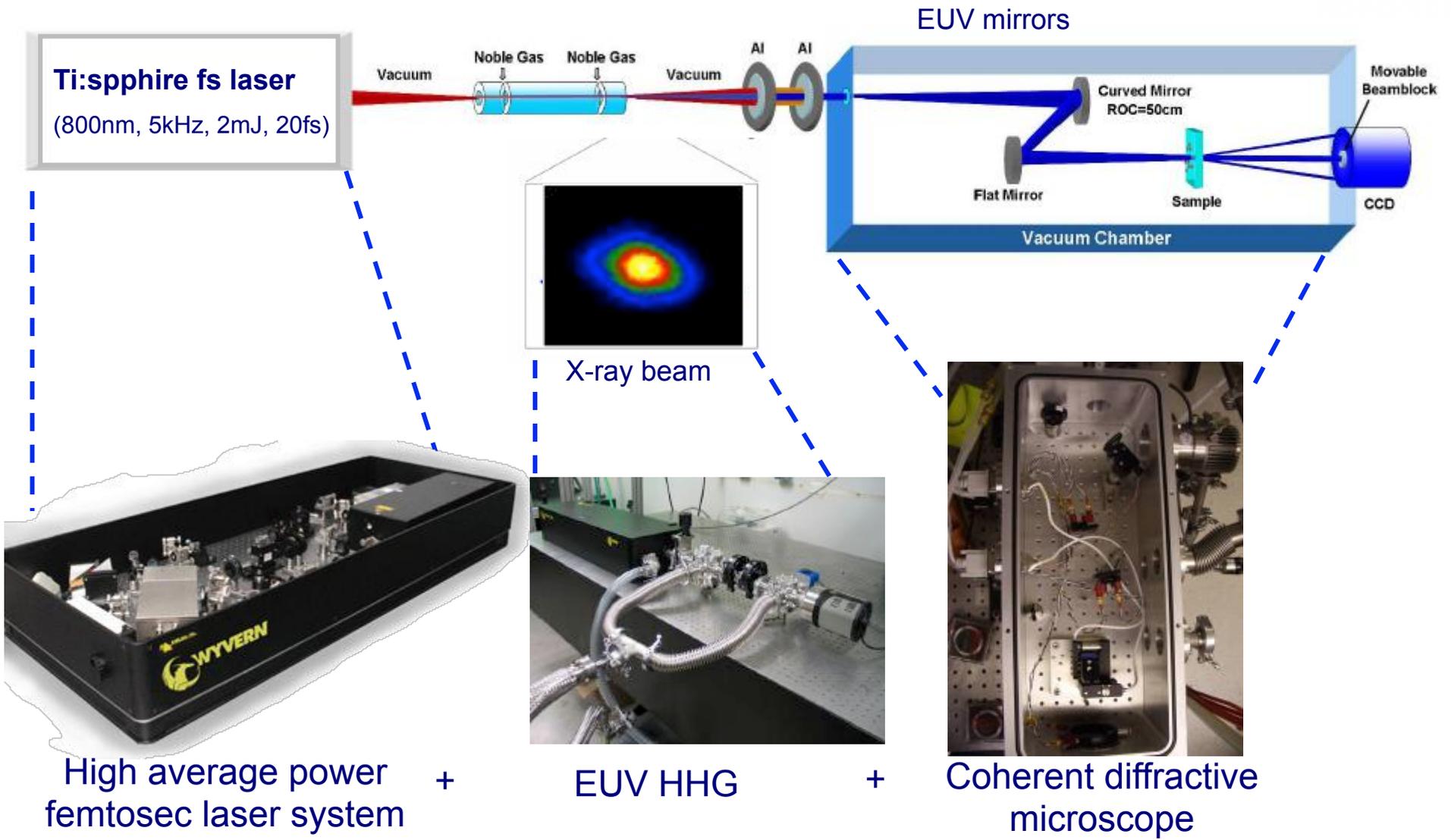
300-1000 eV: $10^{-6} - 10^{-7}/\text{eV}$

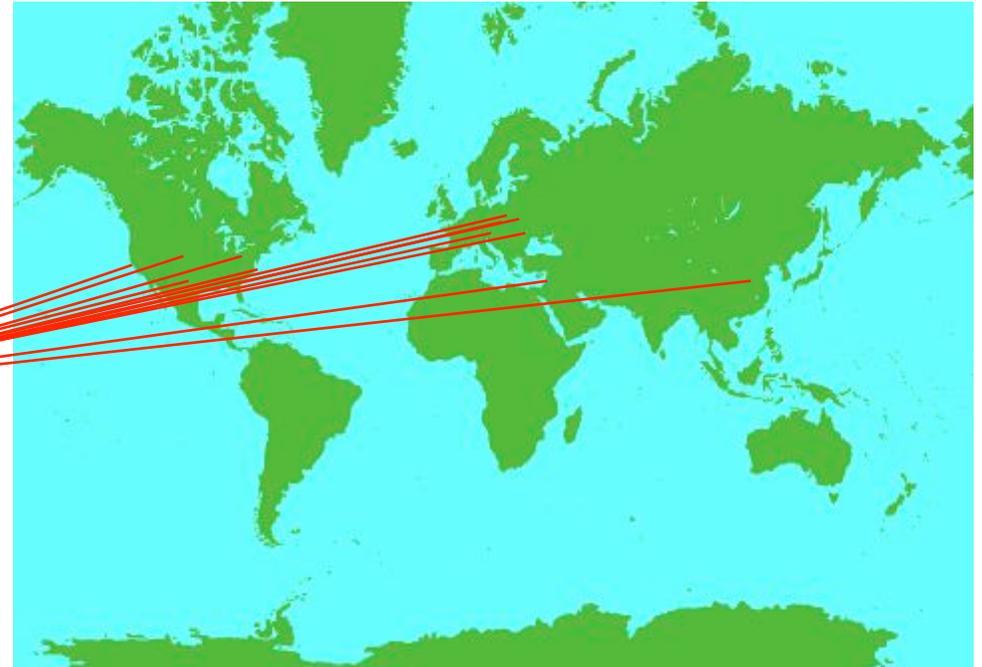
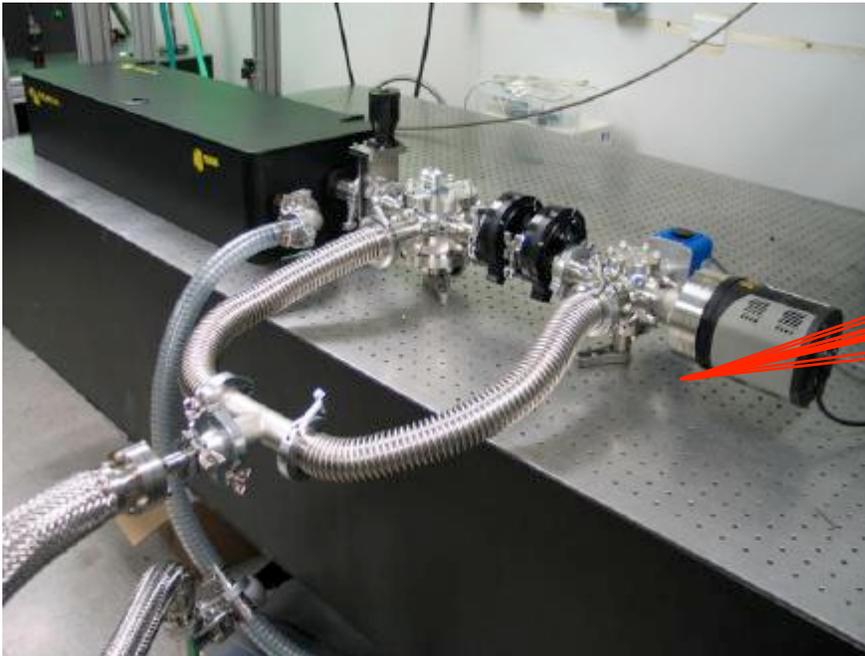
Laser powers: 10 – 50W

EUV power: $\mu\text{W} - 0.5\text{mW}$ (per 1% band)

Limit not known: Increases in efficiency and photon energy very likely

Opt. Lett. **33**, 2128 (2008)
PNAS **106**, 10516 (2009)
Nature Photonics **4**, 822 (2010)
Chen et al., PRL **105**, 173901 (2010))
Science **336**, 1287 (2012)





- First commercial ultrafast coherent EUV source
- Operated at CLEO exhibit in May 2009
- Commercial, integrated, UHV-compatible system installed in Germany (4), Israel (2), MIT(1), Caltech (1), China (1) and Bulgaria (1) for applications in materials science
- Used successfully by many groups

KMLabs Inc.™

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extreme uv

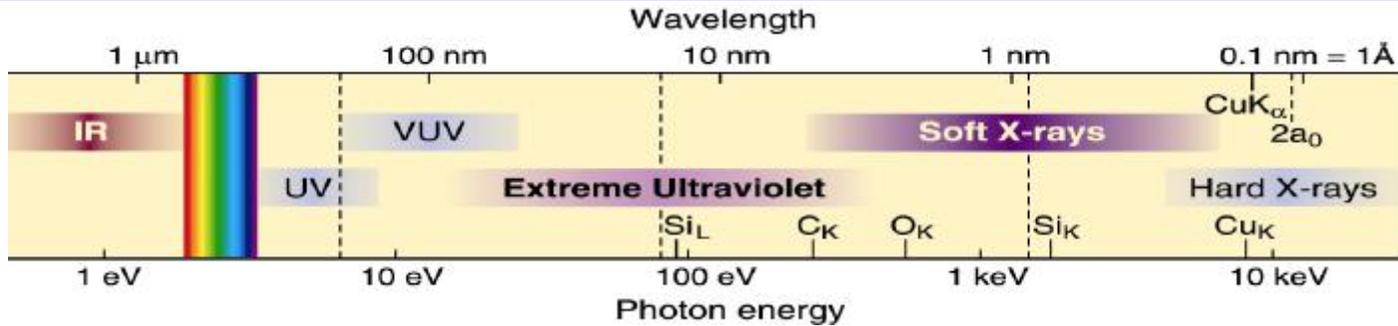
DRAGON AMPLIFIERS >> | REDDRAGON AMPLIFIERS >>

XUUS™ - eXtreme Ultraviolet Ultrafast Source

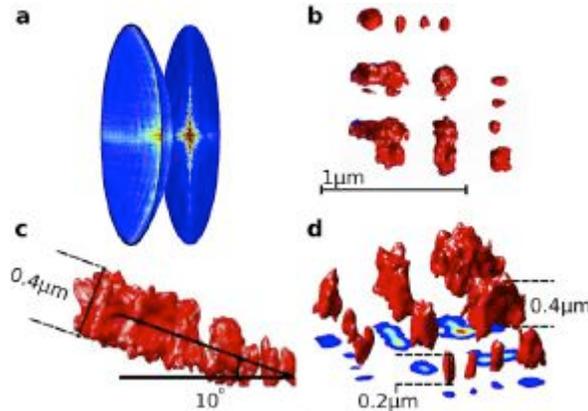
A tabletop device to enable KMLabs Dragon™ and RedDragon™ users to convert the IR ultrafast amplifier output to the Extreme UV (EUV) or Soft X-Ray region. The EUV light is fully coherent and "laser like" light, with user-selectable peak wavelengths between 17 and 47 nm. Applications include EUV lithographic mask metrology, lensless imaging, and high spatial/ temporal resolution pump-probe experiments.

- Optimized for use with Dragon™ and RedDragon™ series ultrafast amplifiers
- Cell design based upon many years of R&D and engineering optimization
- Proven in landmark publications in Science
- EUV generation by High Harmonic Generation (HHG) in noble gases
- Phase-matched conversion in selected noble gas
- Wavelength is user-selectable, though not arbitrarily tunable
- Highly coherent "laser-like" EUV light
- User-selectable peak wavelength between 26 eV (47 nm) and 70 eV (17 nm)

Unique ultrafast coherent tabletop X-ray source

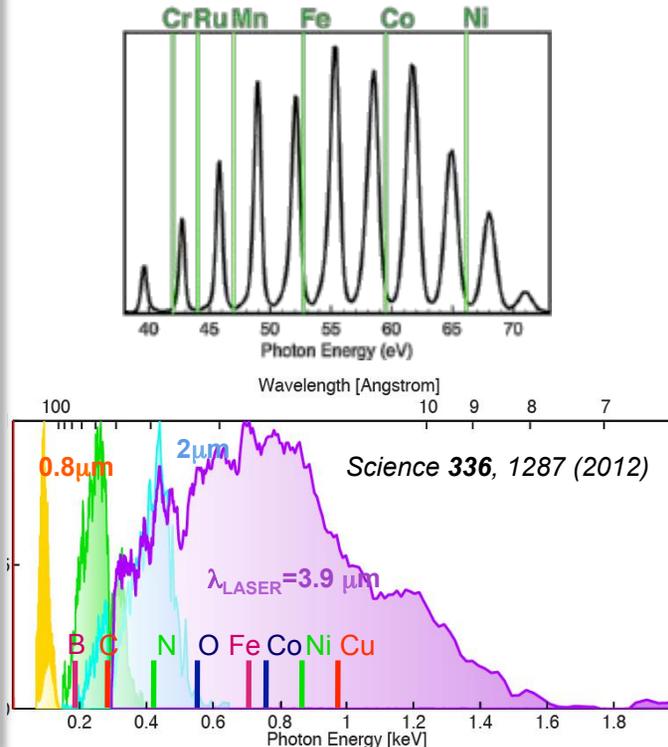


SPATIAL: 3D near- λ imaging

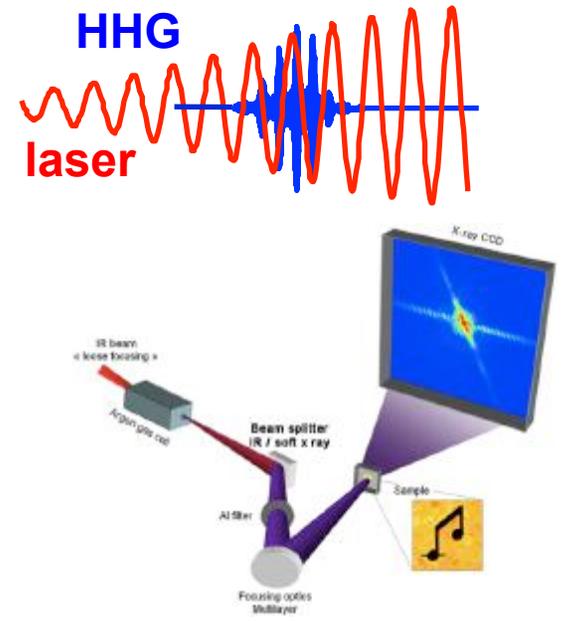


Nature **463**, 214 (2010)
Optics Express **19**, 22470 (2011)

SPECTRAL: Elemental and chemical specificity

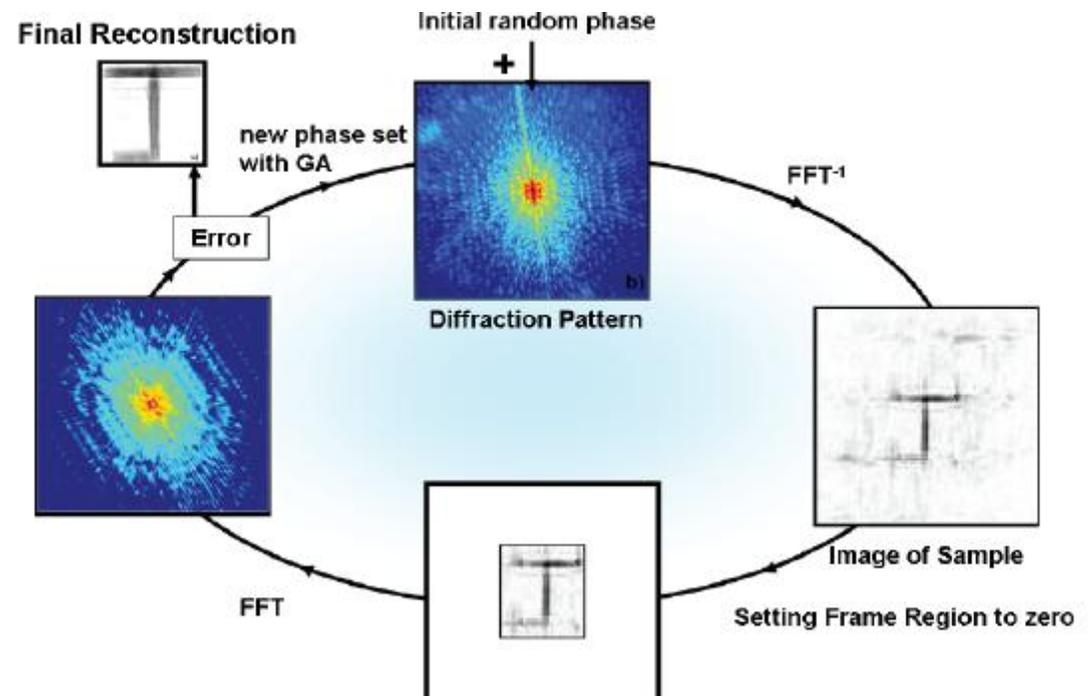
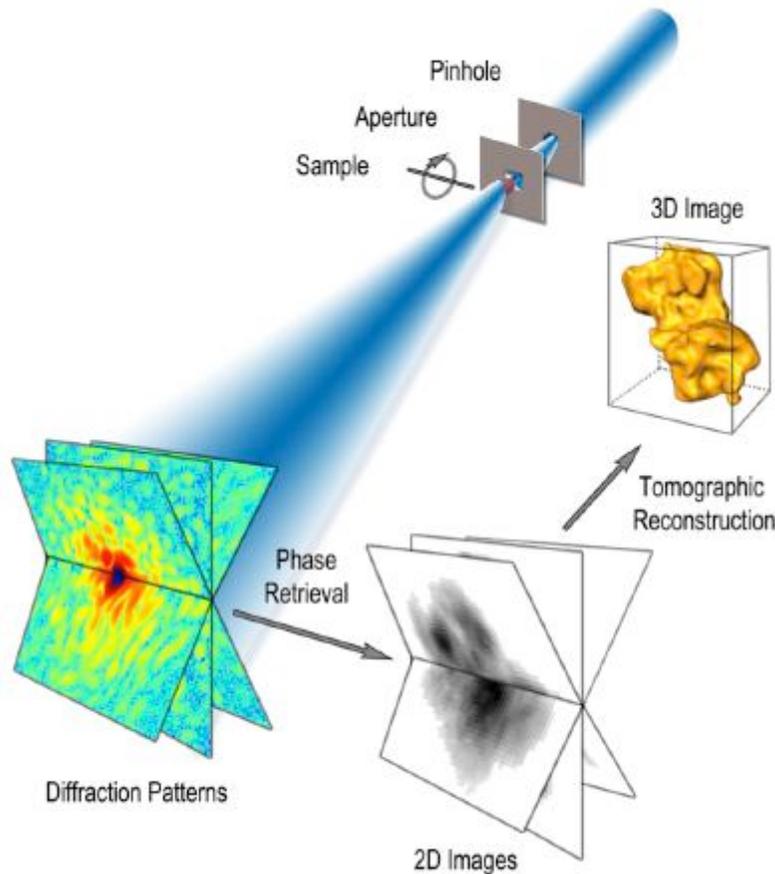


TEMPORAL: Ultrafast, single shot



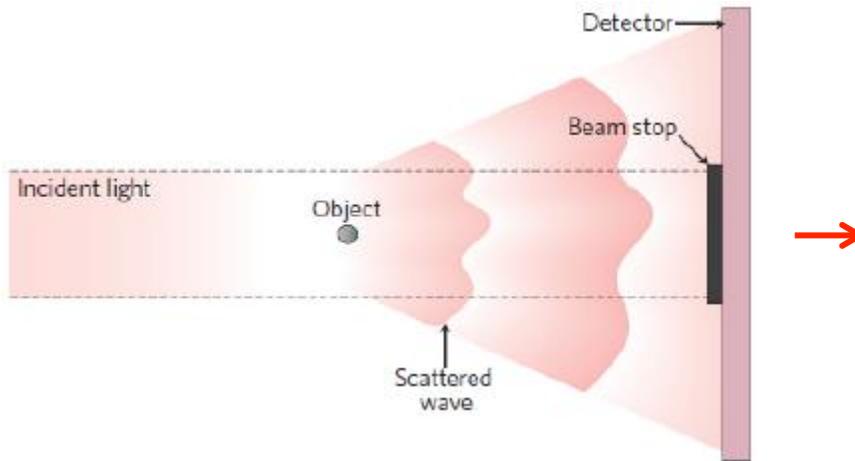
Phys. Rev. Lett. **103**, 028104 (2009)
Nature News and Views **460**, 1088 (2009)

- Diffraction-limited imaging $\approx \lambda/2NA$
- Image thick samples
- Inherent contrast of x-rays
- Robust, insensitive to vibrations
- Needs a coherent beam and isolated sample

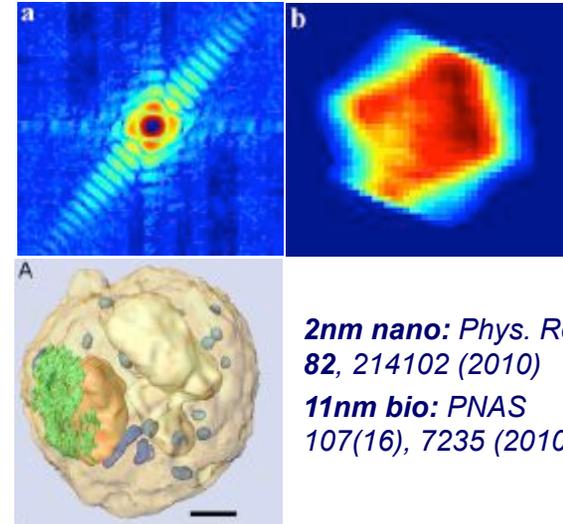


Sayre, *Acta Cryst* **5**, 843 (1952)
Miao et al., *Nature* **400**, 342 (1999)

Coherent Diffractive Imaging (CDI)



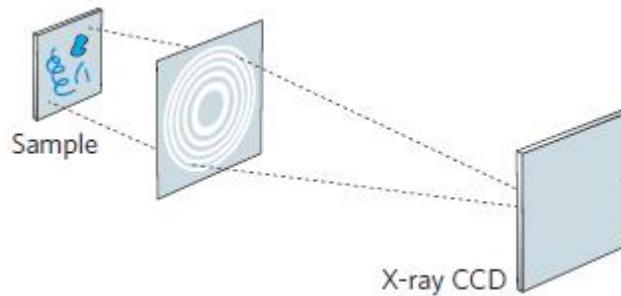
- ✓ λ limited resolution ($\approx 2\text{nm}$)
- ✓ Robust to vibrations



2nm nano: *Phys. Rev. B* **82**, 214102 (2010)
11nm bio: *PNAS* **107**(16), 7235 (2010)

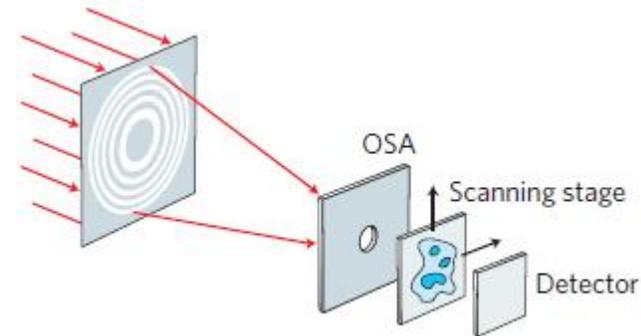
Miao et al., Nature **400**, 342 (1999)
Chapman and Nugent, Nature Photonics, **4**, 833 (2010)

Full-field Zone Plate Microscopy



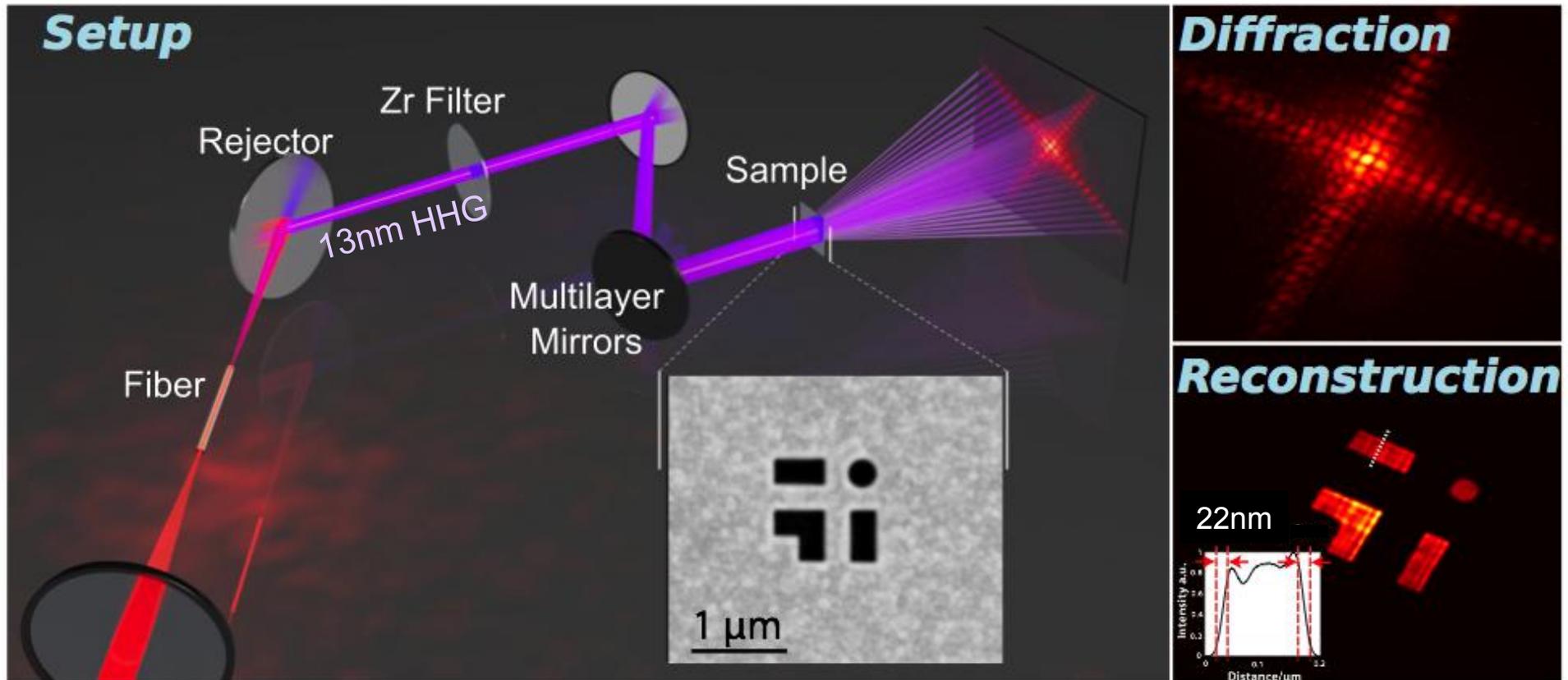
Sakdinawat and Attwood, Nature Photonics, **4**, 840 (2010)

Scanning Transmission X-ray Microscopy



- ✓ Well established ($\approx 13\text{nm}$)
- ✓ Real image

$NA \approx 0.6 - 0.8$

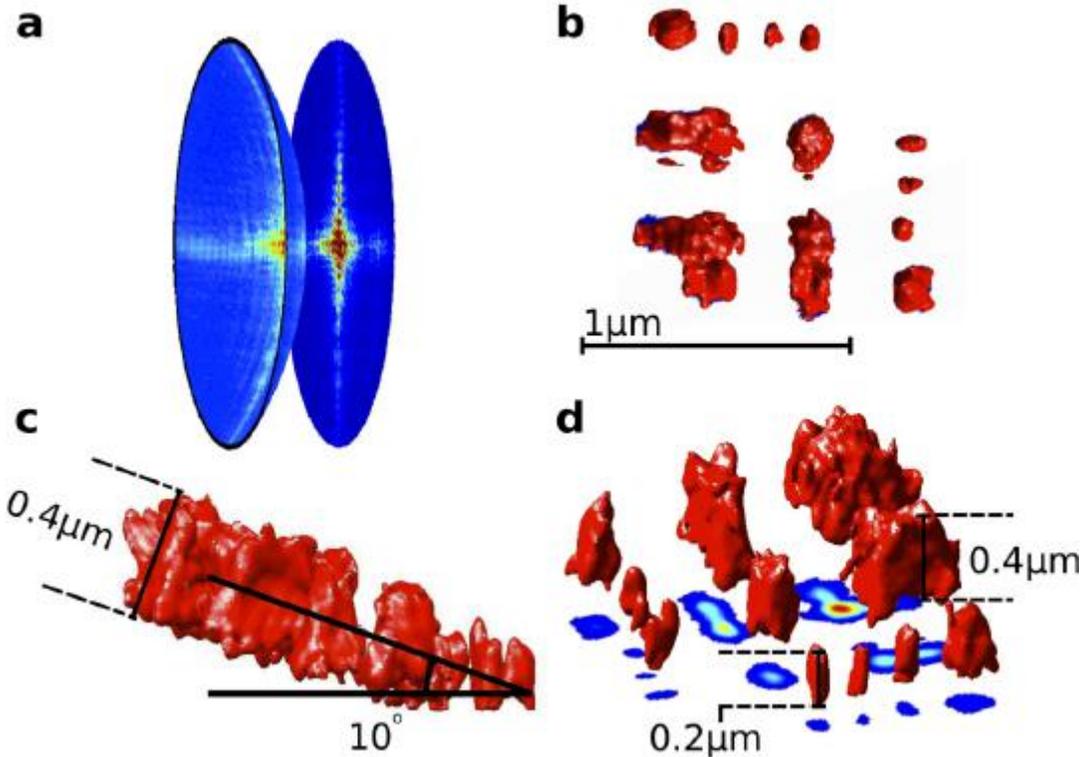
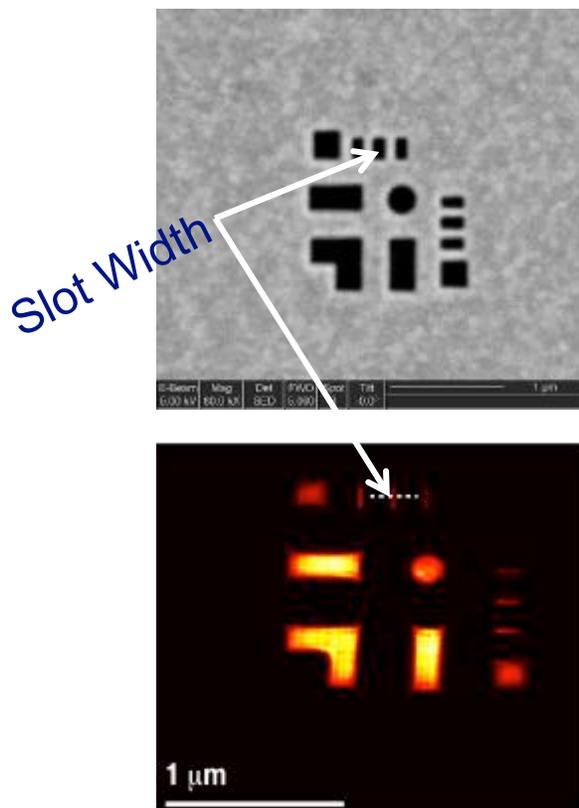


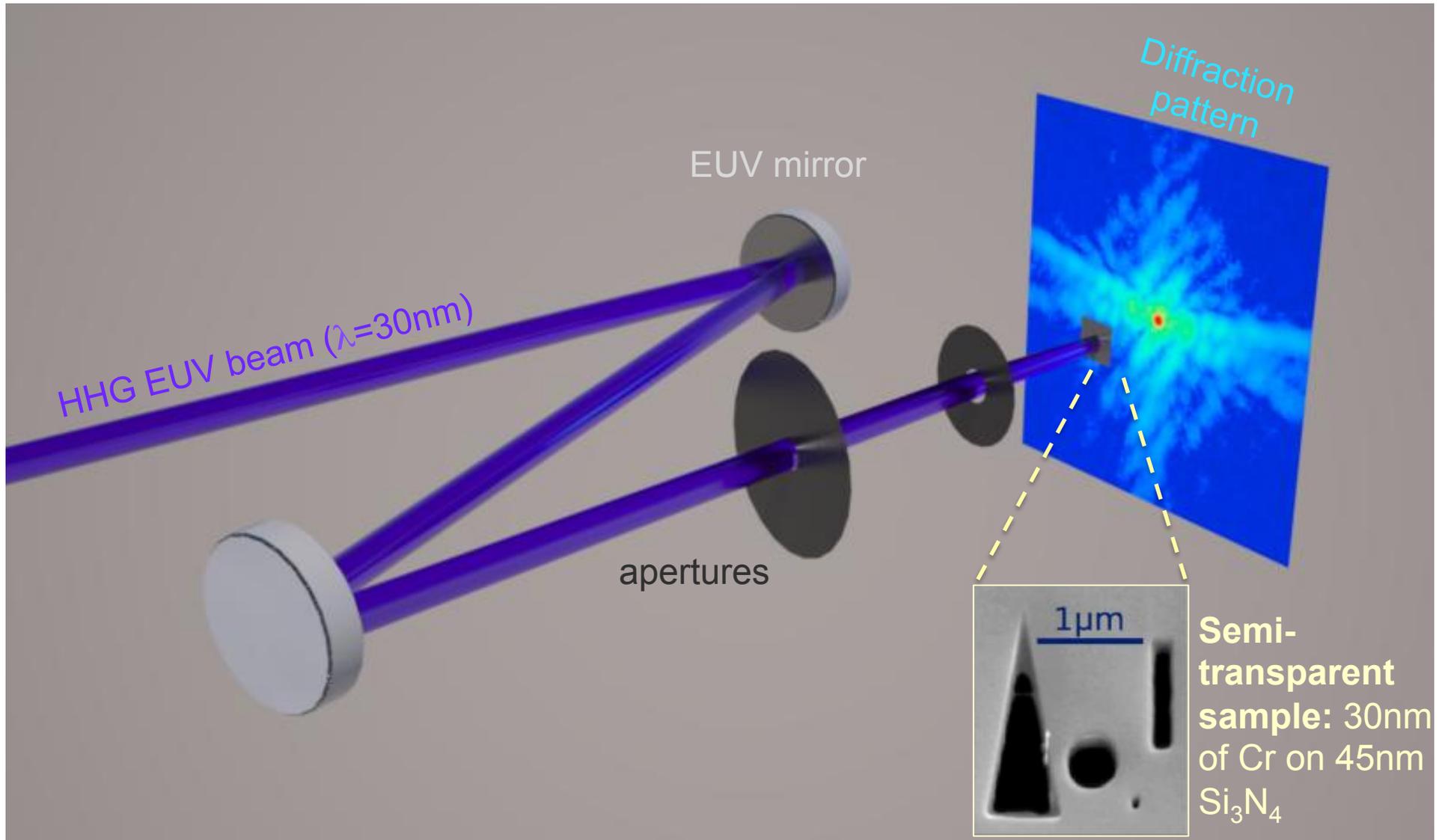
PRL **99**, 098103 (2007); *Nature* **449**, 553 (2007); *PNAS* **105**, 24 (2008);
Nature Photon. **2**, 64 (2008); *OL* **34**, 1618 (2009); *Optics Express* **19**, 22470 (2011)

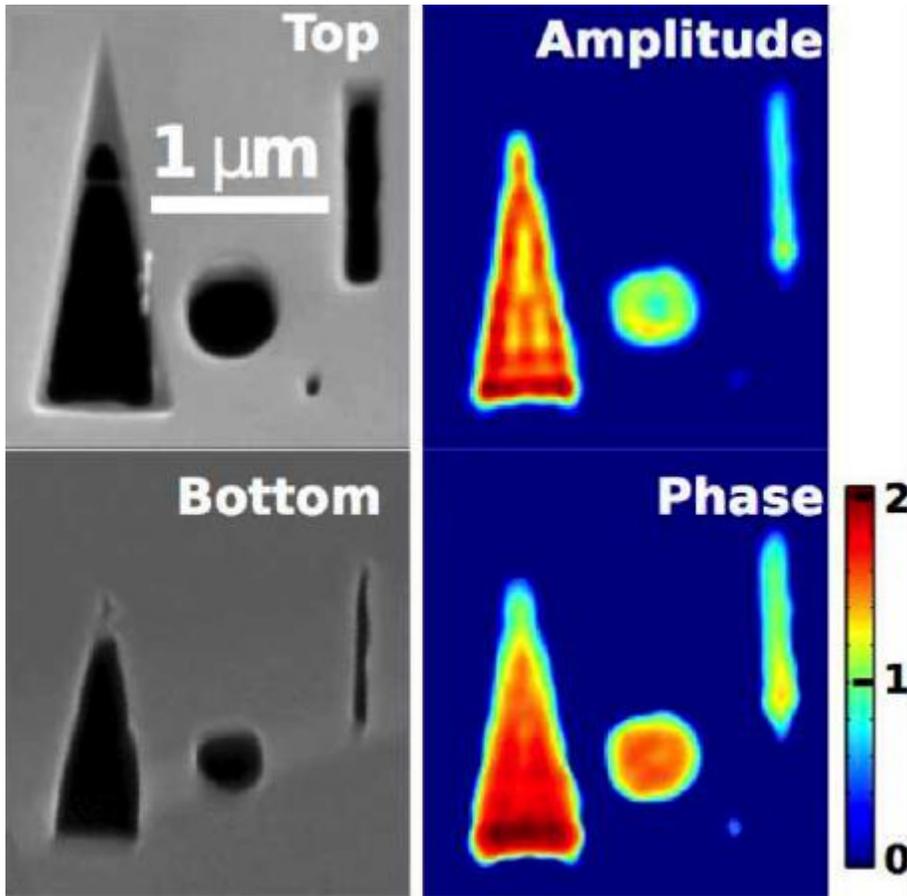
Three-dimensional structure determination from a single view

NATURE | Vol 463 | 14 January 2010

Kevin S. Raines^{1,2}, Sara Salha^{1,2}, Richard L. Sandberg^{4,5}, Huaidong Jiang^{1,2}, Jose A. Rodríguez³, Benjamin P. Fahimian^{1,2}, Henry C. Kapteyn^{4,5}, Jincheng Du^{6,7} & Jianwei Miao^{1,2}

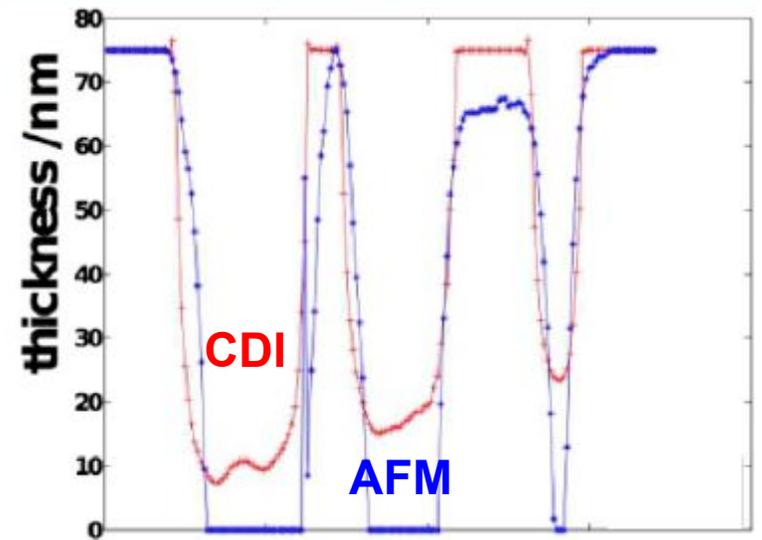
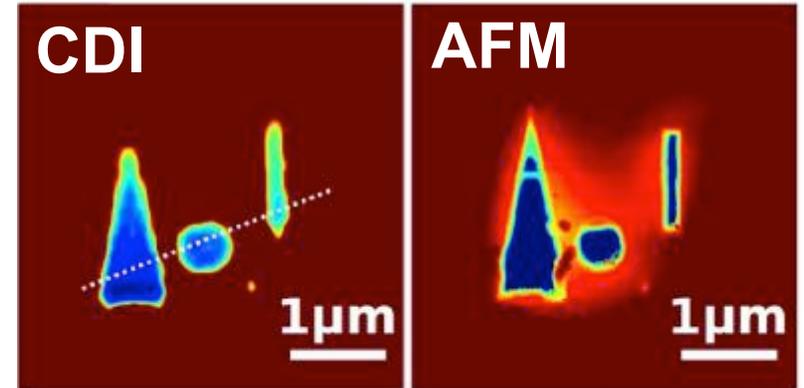






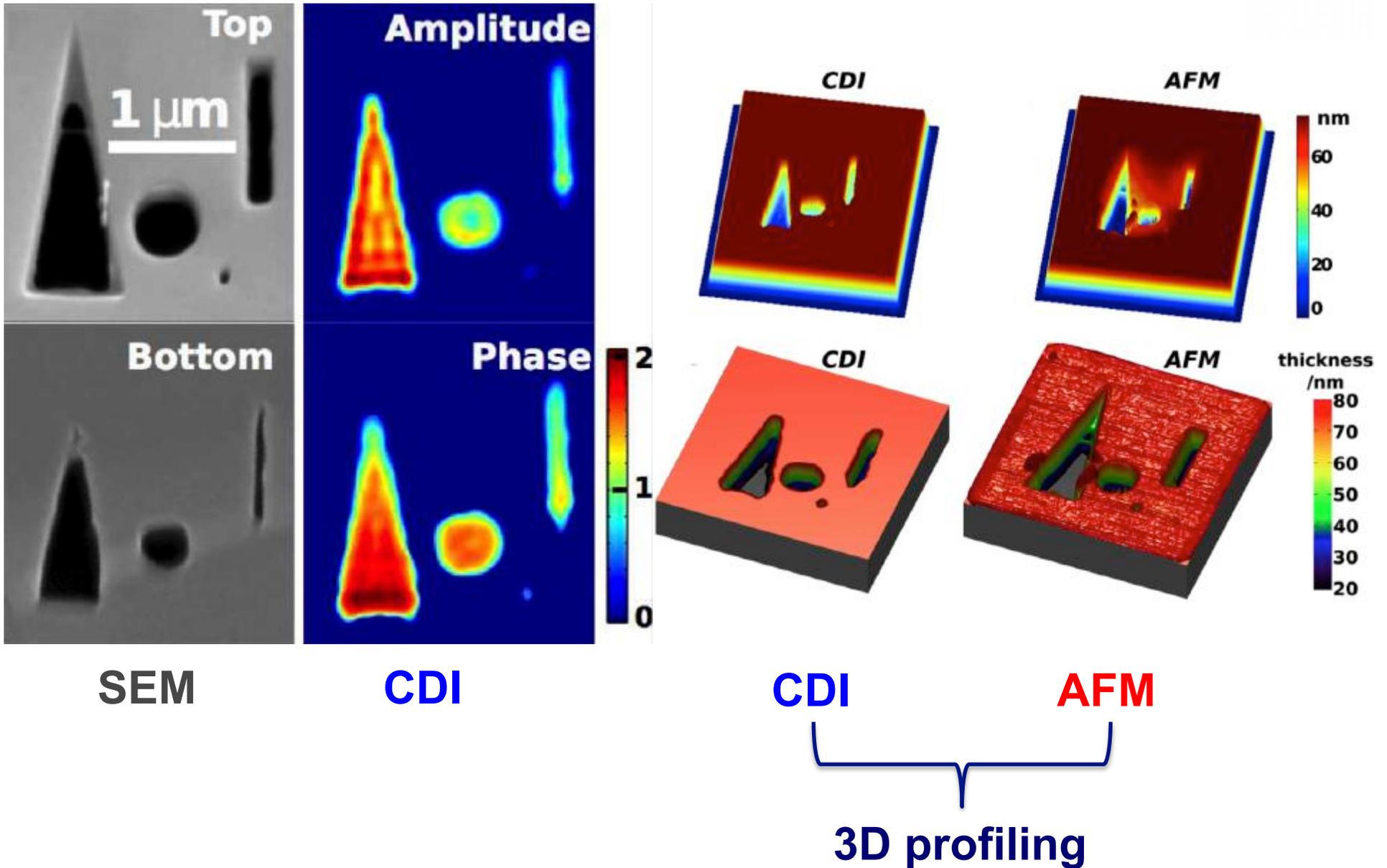
SEM

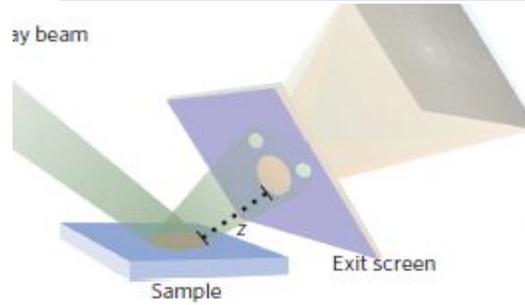
CDI



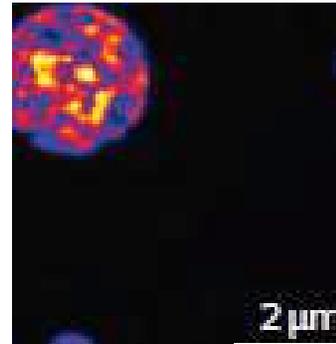
Thickness map

- Semi-transparent background – can extract thickness
- 50nm hole not completely drilled through: 48nm (CDI) vs 52nm (AFM)

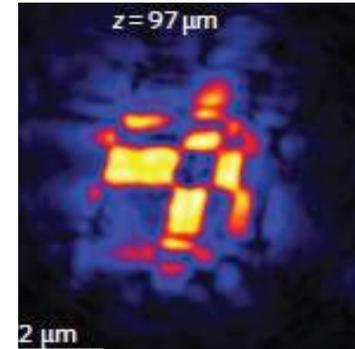




Nature Photon.
5, 243 (2011)

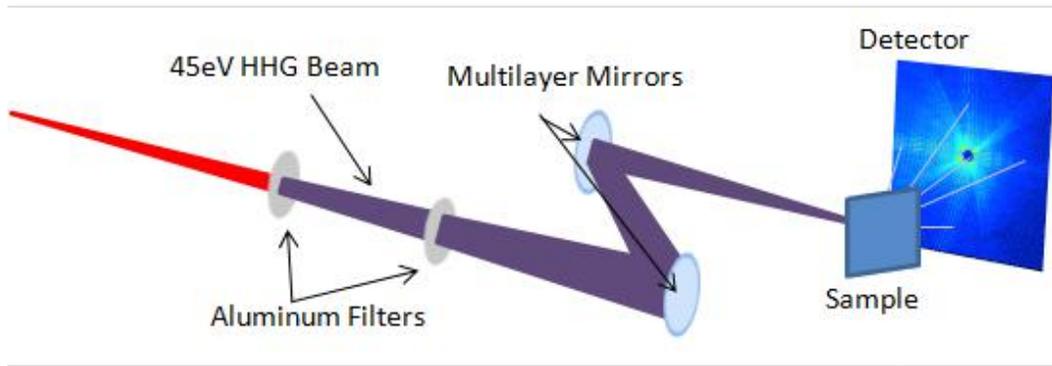
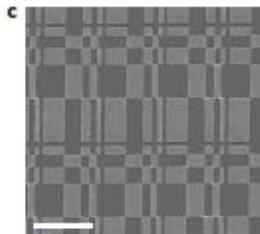
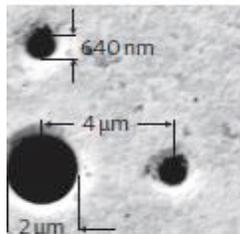


Reconstruction
at Exit Screen



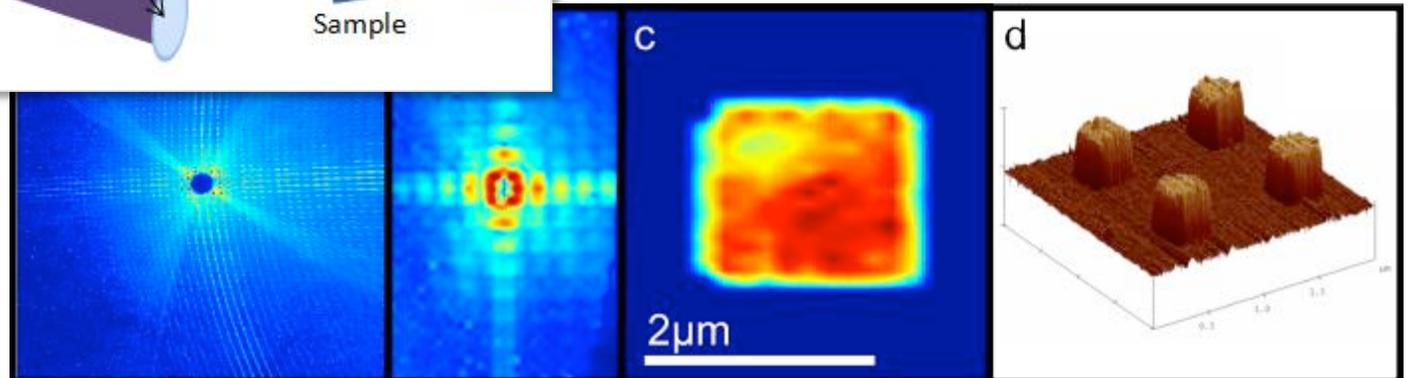
Field at sample

ALS

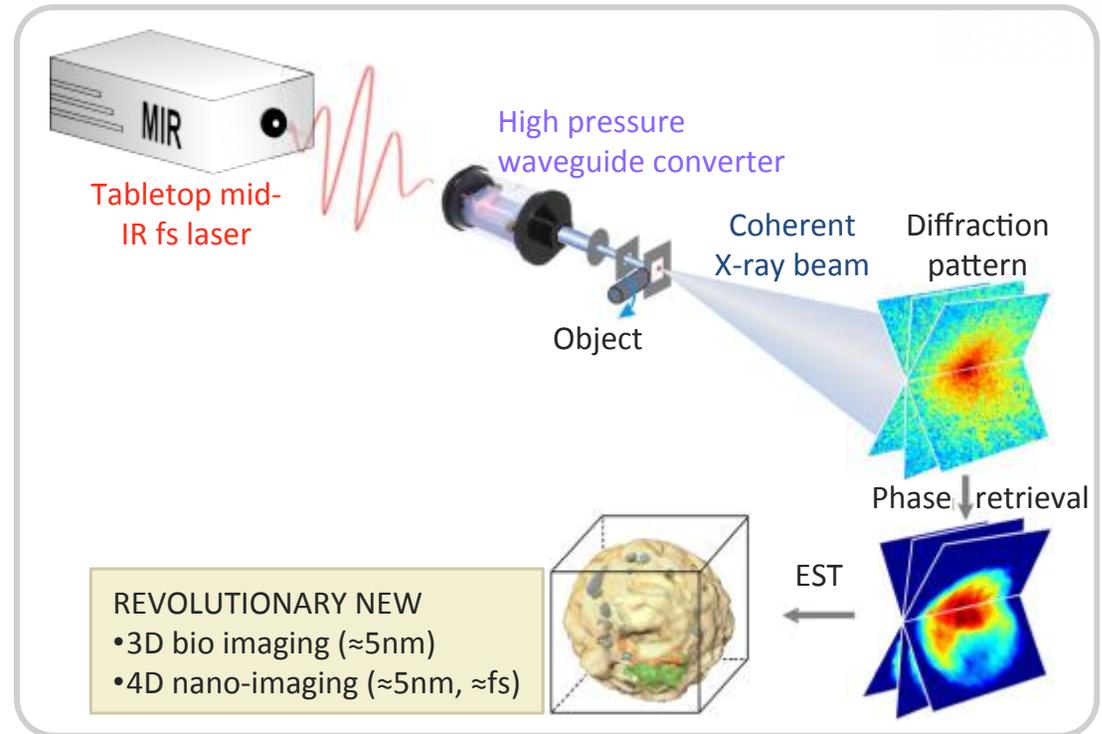


Tabletop HHG

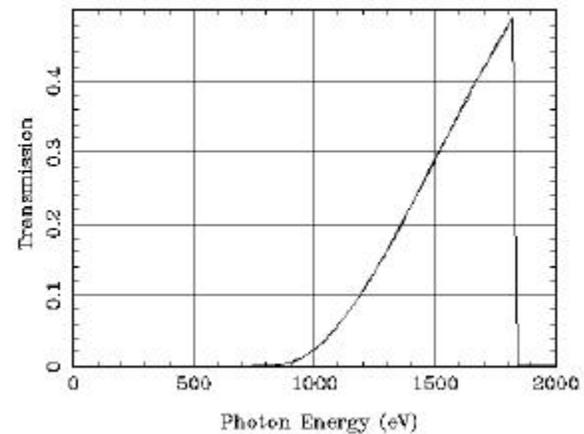
Opt. Express **20**,
19050 (2012)

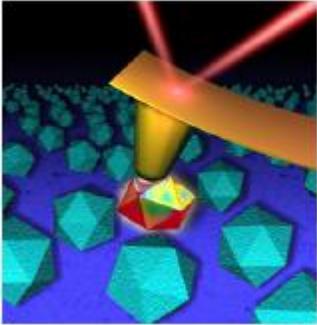


- General scanning reflection mode coherent microscope (2013)
- Shorter wavelengths to increase the NA, spatial resolution $\approx 5\text{nm}$, and 3D imaging of thick samples
- Advanced low-dose EST algorithms (*Miao, Nature 483, 444 (2012)*)
- Rate limiting step – need $3\mu\text{m}$ lasers and advanced detectors



Si Density=2.33 Thickness=10. microns





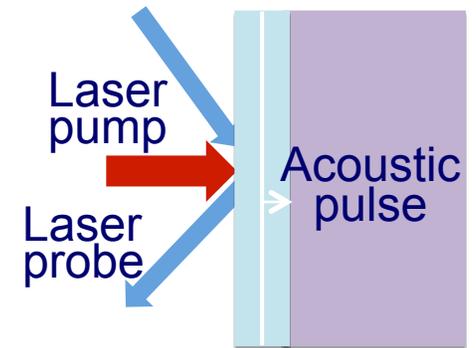
1. Nano-indentation

- ✓ Localized
- ✗ Destructive
- ✗ Substrate contribution

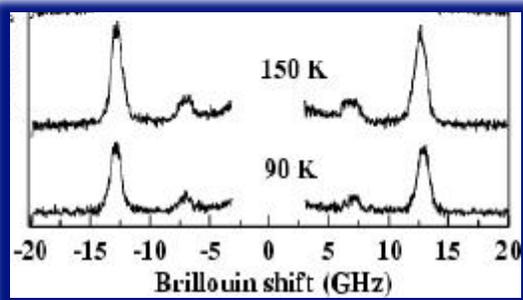
J. Mater. Res 24, 2960 (2009)

2. Optical photoacoustics

- ✓ Non-contact
- ✗ LAW only → assume v
- ✗ Limited to thick films



MRS Bulletin 31, 607 (2006)

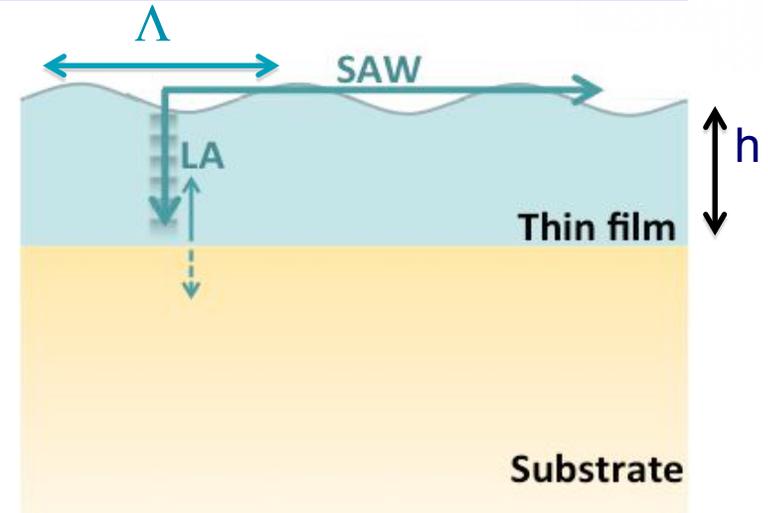


JAP 100, 013507 (2006)

3. Brillouin light scattering

- ✓ Both LA and TA modes
- ✗ Complex interpretation
- ✗ Sensitive to experimental accuracy

- Acoustic waves propagate along (SAW) and into (LAW) surface: EUV x100 more sensitive than visible
- Penetration depth $\approx \zeta \sim \lambda/2\pi$: EUV can characterize **nano-mechanical** elastic properties of $< 10\text{nm}$ films
- Simultaneously extract Young's modulus and Poisson's ratio from LAW and SAW



Young's modulus

$$E = c_{44} \left(\frac{3c_{11} - 4c_{44}}{c_{11} - c_{44}} \right)$$



Poisson's ratio

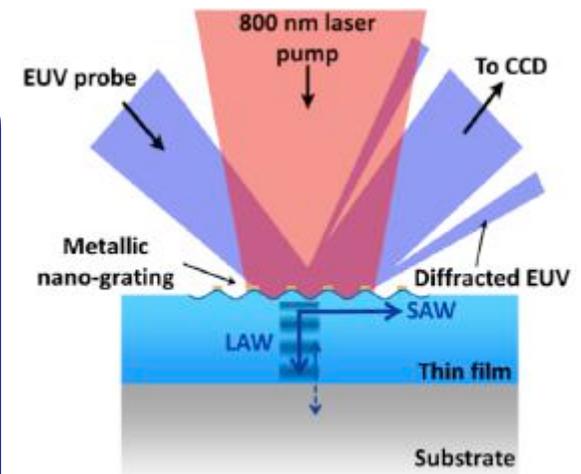
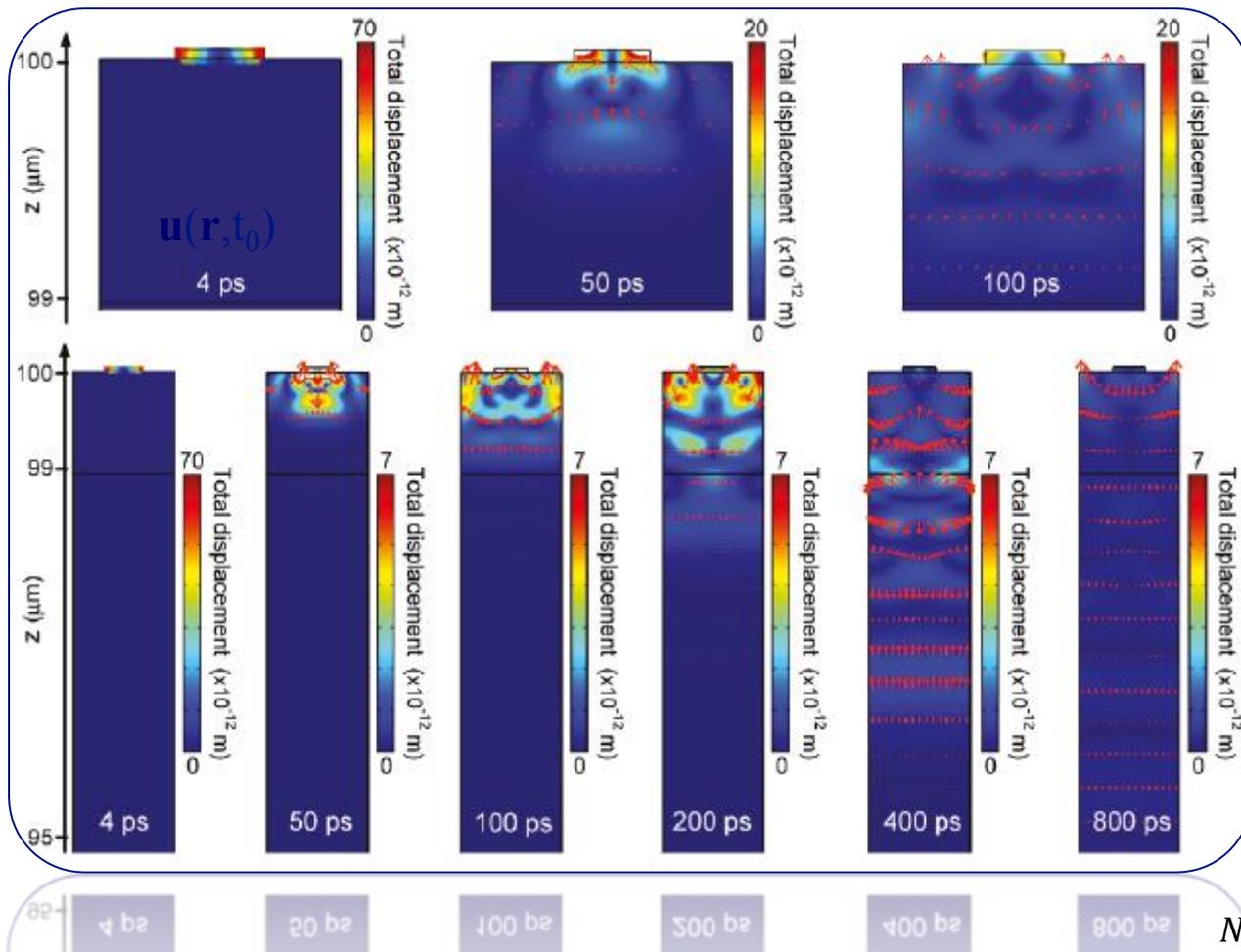
$$\nu = \frac{c_{11} - 2c_{44}}{2(c_{11} - c_{44})}$$



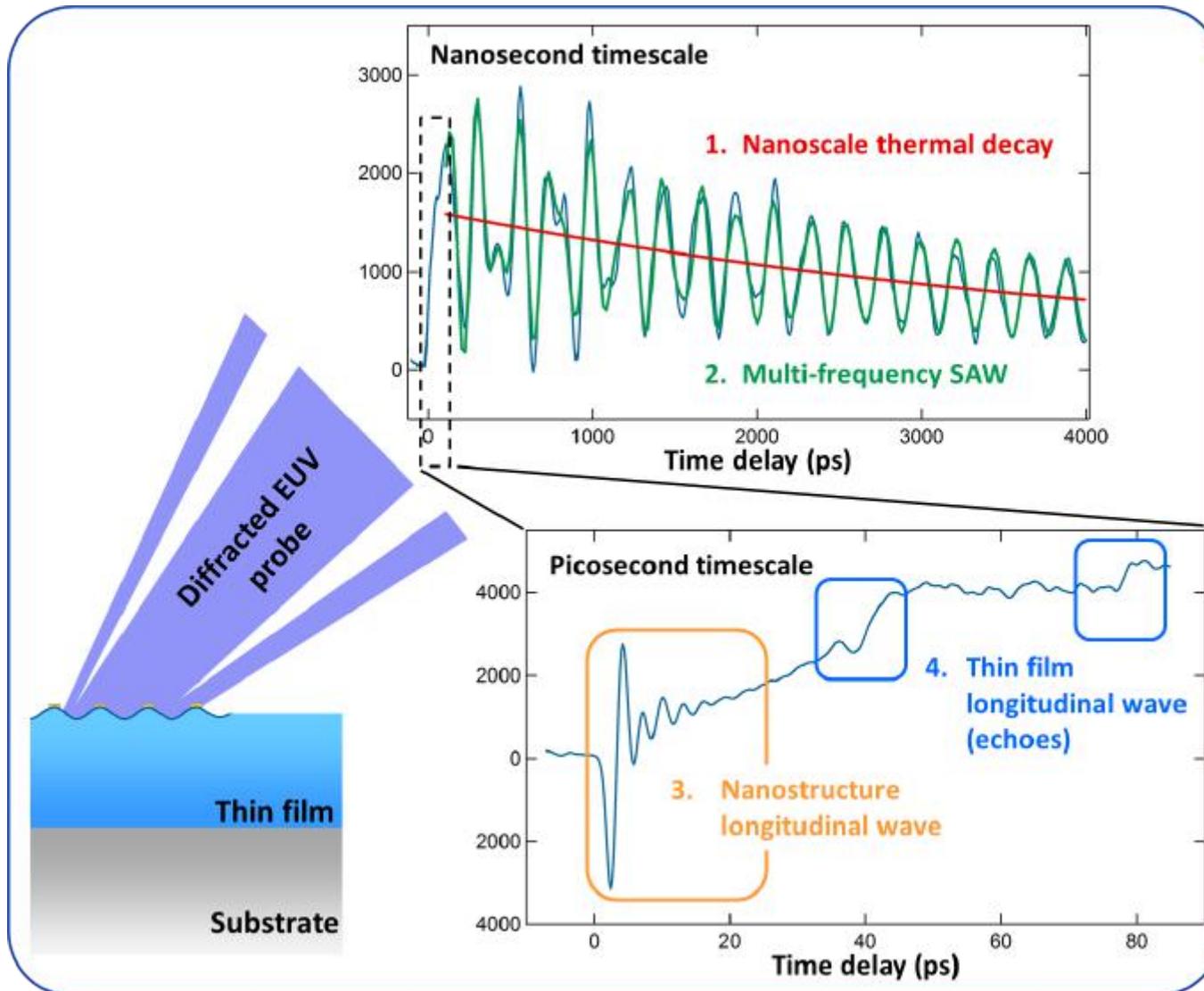
$$v_L = \sqrt{\frac{c_{11}}{\rho}} \text{ Longitudinal acoustic wave}$$

$$v_T = \sqrt{\frac{c_{44}}{\rho}} \text{ Surface acoustic wave}$$

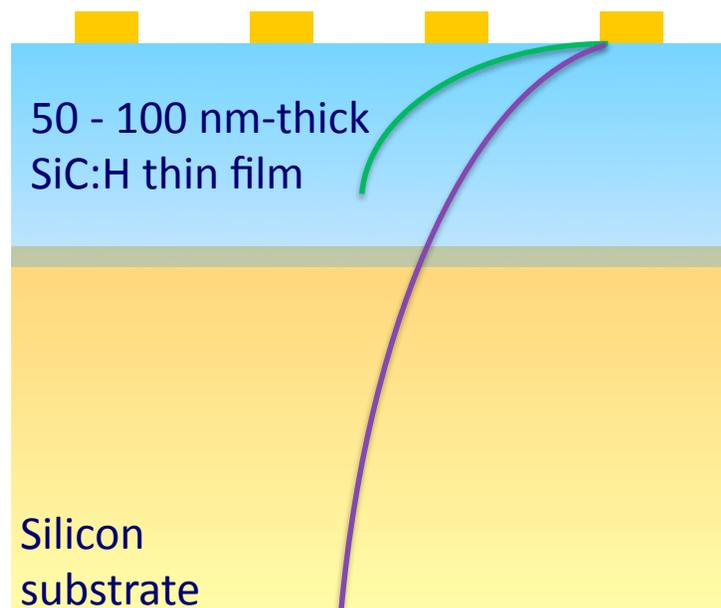
- Launch short-wavelength acoustic waves from IR impulsive excitation of nano-gratings (CXRO)
- Detect \approx picometer displacements using coherent EUV beams



- Diffracted EUV signal from thin film sample has four components:



- Acoustic wave penetration depth $\zeta \sim \Lambda/\pi$
- Visible light will not diffract from short wavelength acoustic waves
- The measured transverse velocity changes for shorter wavelengths as the SAW is more and more confined within the thin film.

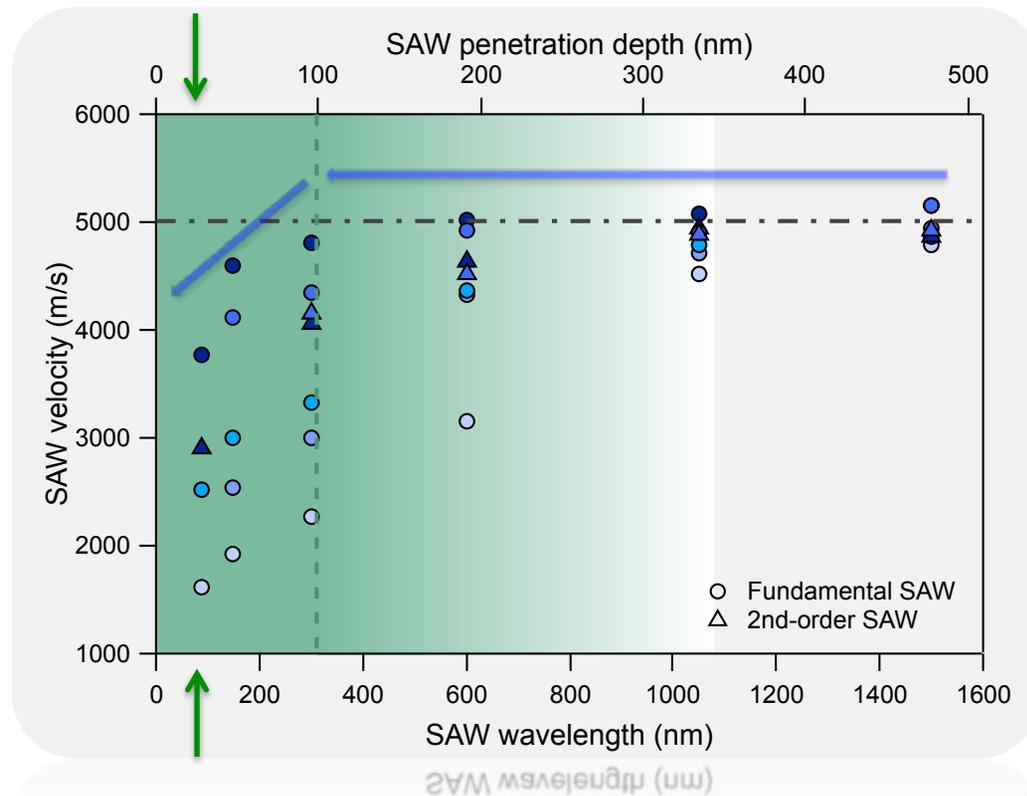


Short Λ SAW confined within film
 $v_T = 2800 \text{ m/s}$ (consistent with SiC:H)

Medium Λ SAW evenly in film and substrate
 $v_T = 4250 \text{ m/s}$ (consistent with SiC:H)

Long Λ SAW primarily in substrate
 $v_T = 4900 \text{ m/s}$ (consistent with Si)

- **Large-period gratings:** SAW velocity consistent with literature for Si
- **Short-period gratings:** slower velocities associated with softer film materials
- Detected 45nm SAWs - confined to 10nm depths



$$\zeta \sim \Lambda / 2\pi$$

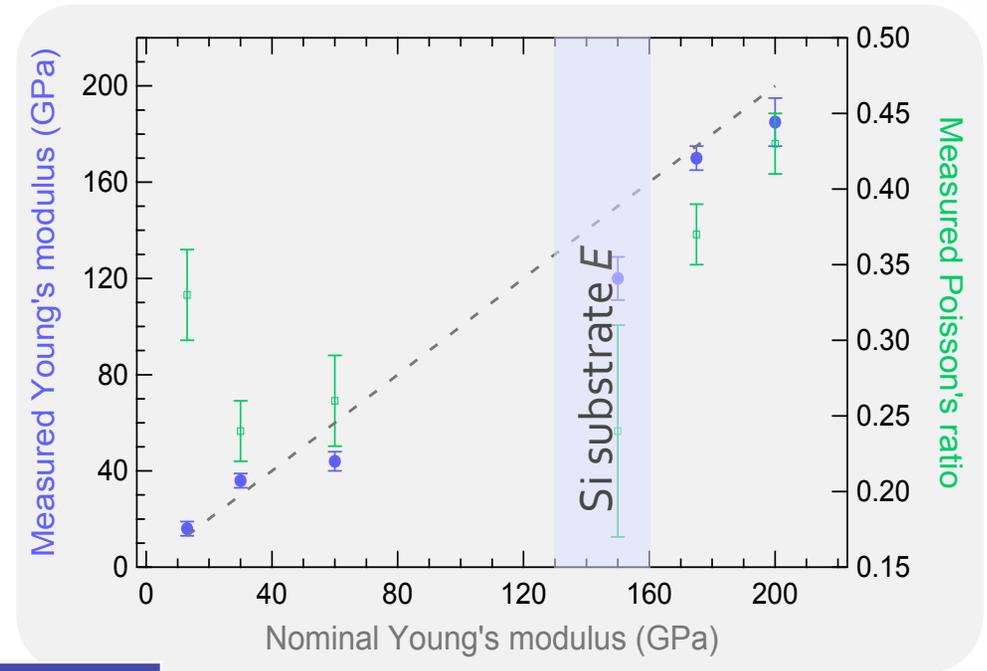
E = 200 GPa



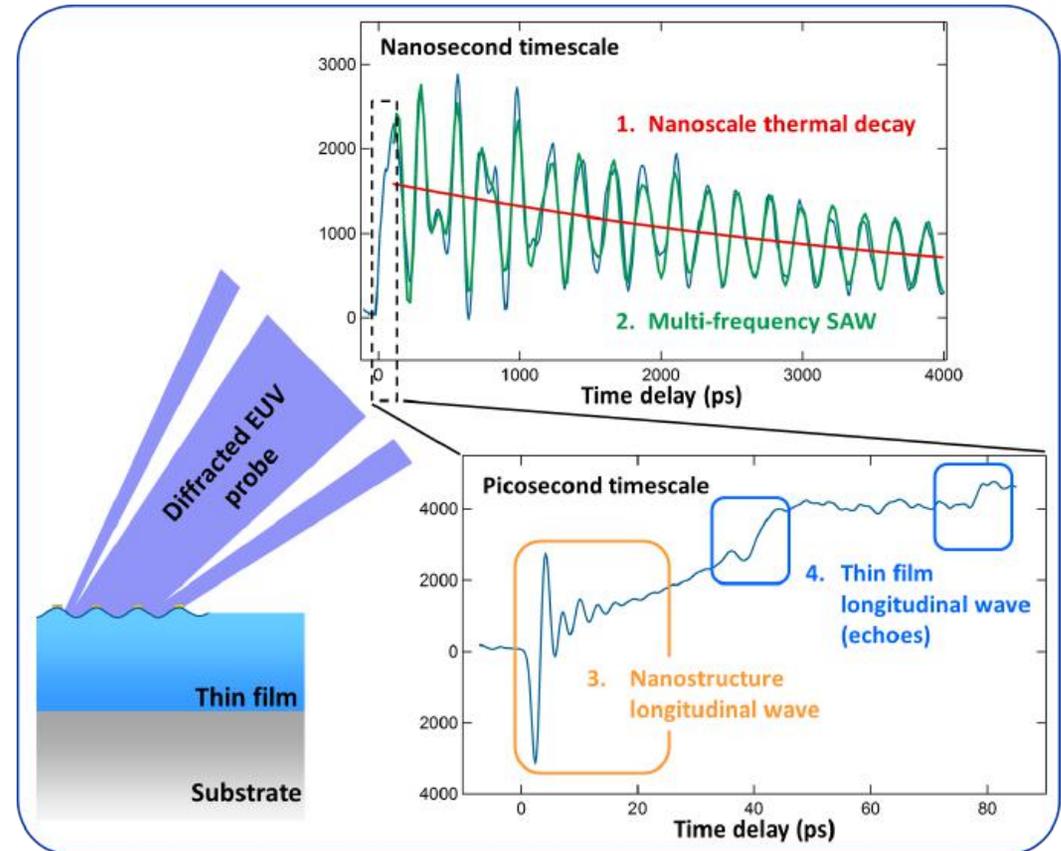
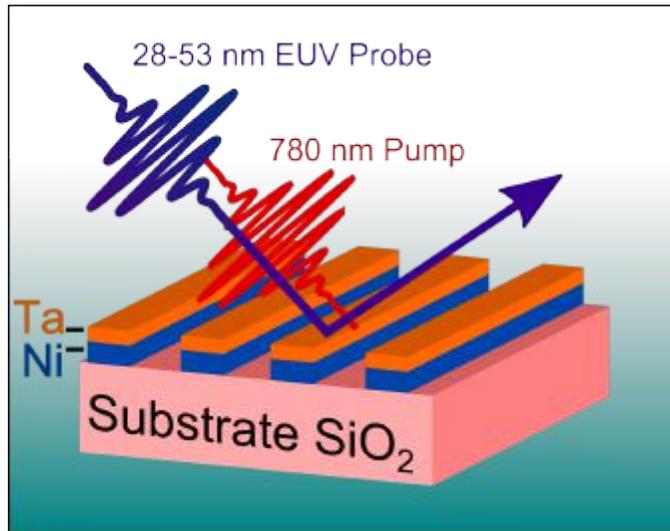
Softer
SiC:H films

E = 13 GPa

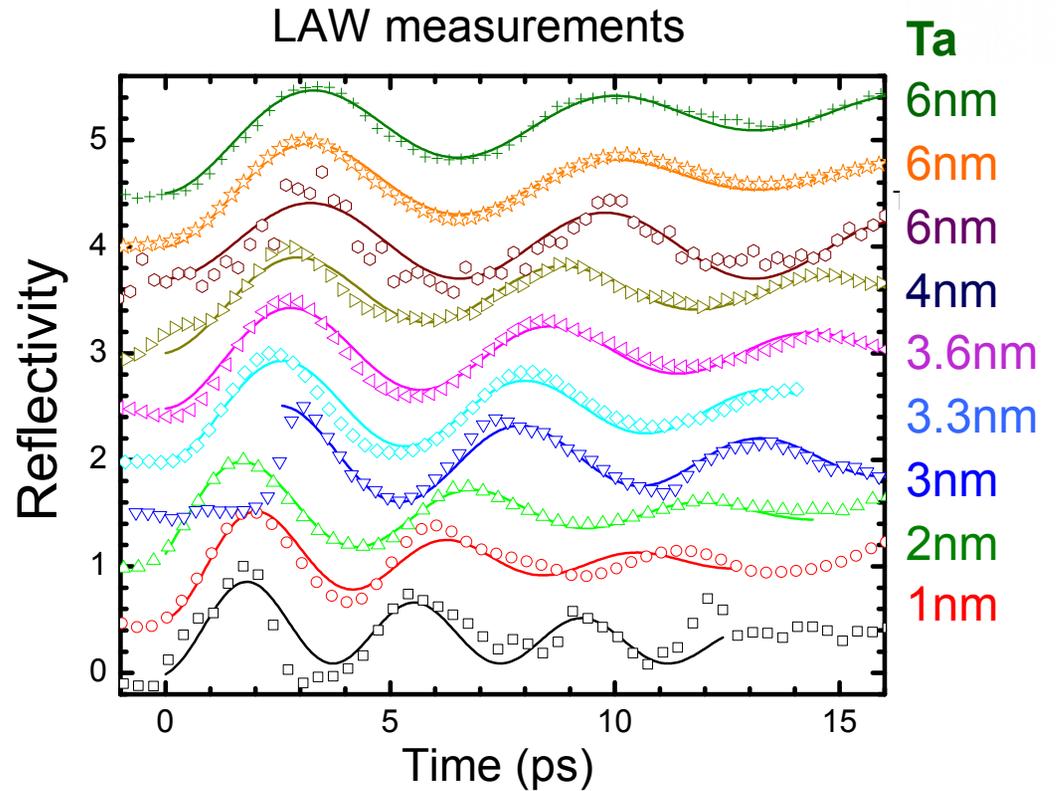
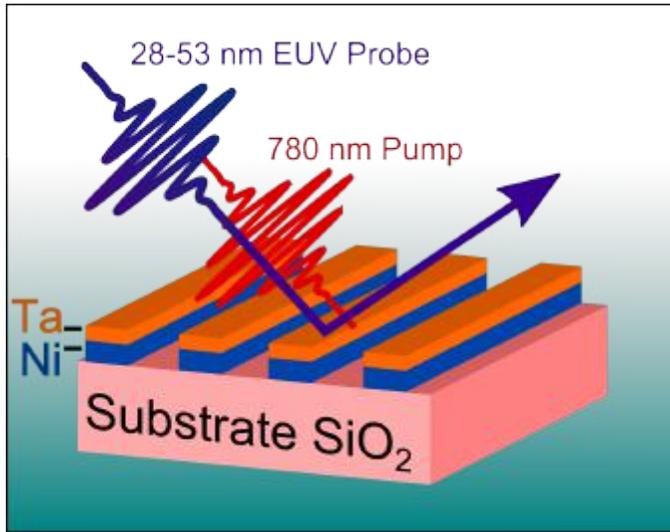
- Compare nominal and measured Young's modulus
- Measure Poisson's ratio using LAW
- Improvements in many aspects can significantly increase accuracy



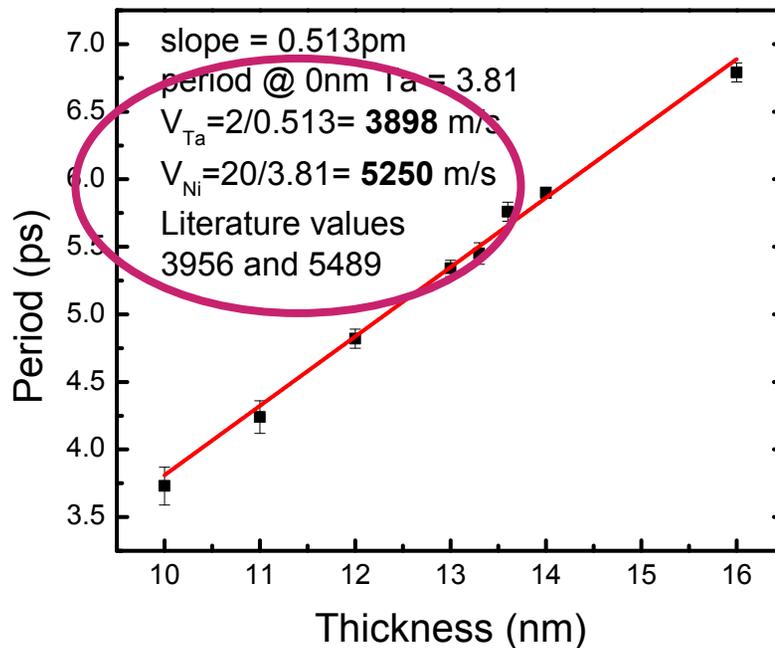
Nominal E	Measured E	Measured ν
13 GPa (100nm)	16 ± 3 GPa	0.33 ± 0.03
30 GPa (100nm)	36 ± 3 GPa	0.24 ± 0.02
60 GPa (100nm)	44 ± 4 GPa	0.26 ± 0.03
150 GPa (100nm)	120 ± 9 GPa	0.24 ± 0.07
175 GPa (100nm)	170 ± 5 GPa	0.37 ± 0.02
200 GPa (50nm)	185 ± 10 GPa	0.43 ± 0.02

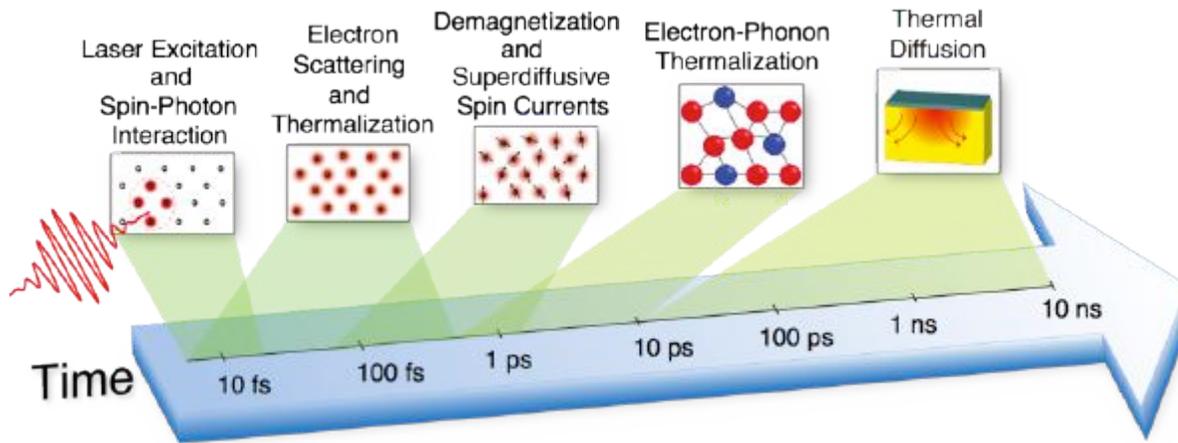


- Presence of additional 1nm layer on nanostructure is easily detected by difference in longitudinal wave velocity
- What is our detection limit?



- Sensitive to pm deflection in holographic mode
- Retrieve layer-sensitive velocities
- **Next steps** – 1) extract film density and elastic properties of individual layers as film builds up, and 2) image acoustic/thermal propagation





- No complete microscopic theory of magnetism exists on fs time scales
- High harmonics enable ultrafast, element-specific, spin dynamics to be probed at multiple sites simultaneously

Even in a strongly exchange-coupled Fe-Ni ferromagnetic alloy, the dynamics of the individual spin sublattices can be different on timescales faster than that characteristic of the exchange interaction energy (10 – 80 fs)

Parallel **Antiparallel**

Large, superdiffusive, spin currents can be launched by a femtosecond laser through magnetic multilayers, to enhance or reduce the magnetization of buried layers, depending on their relative orientation

The structure consists of layers: **Conductor** (Fe, Ru, Ni) and **Scatterer** (Ta), with Si_3N_4 and SiO_2 capping layers. Spin vectors \vec{S}_{Fe} and \vec{S}_{Ni} and spin current \vec{J}_s are shown.

PUBLICATIONS

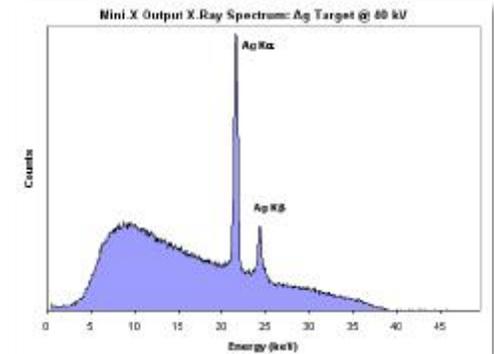
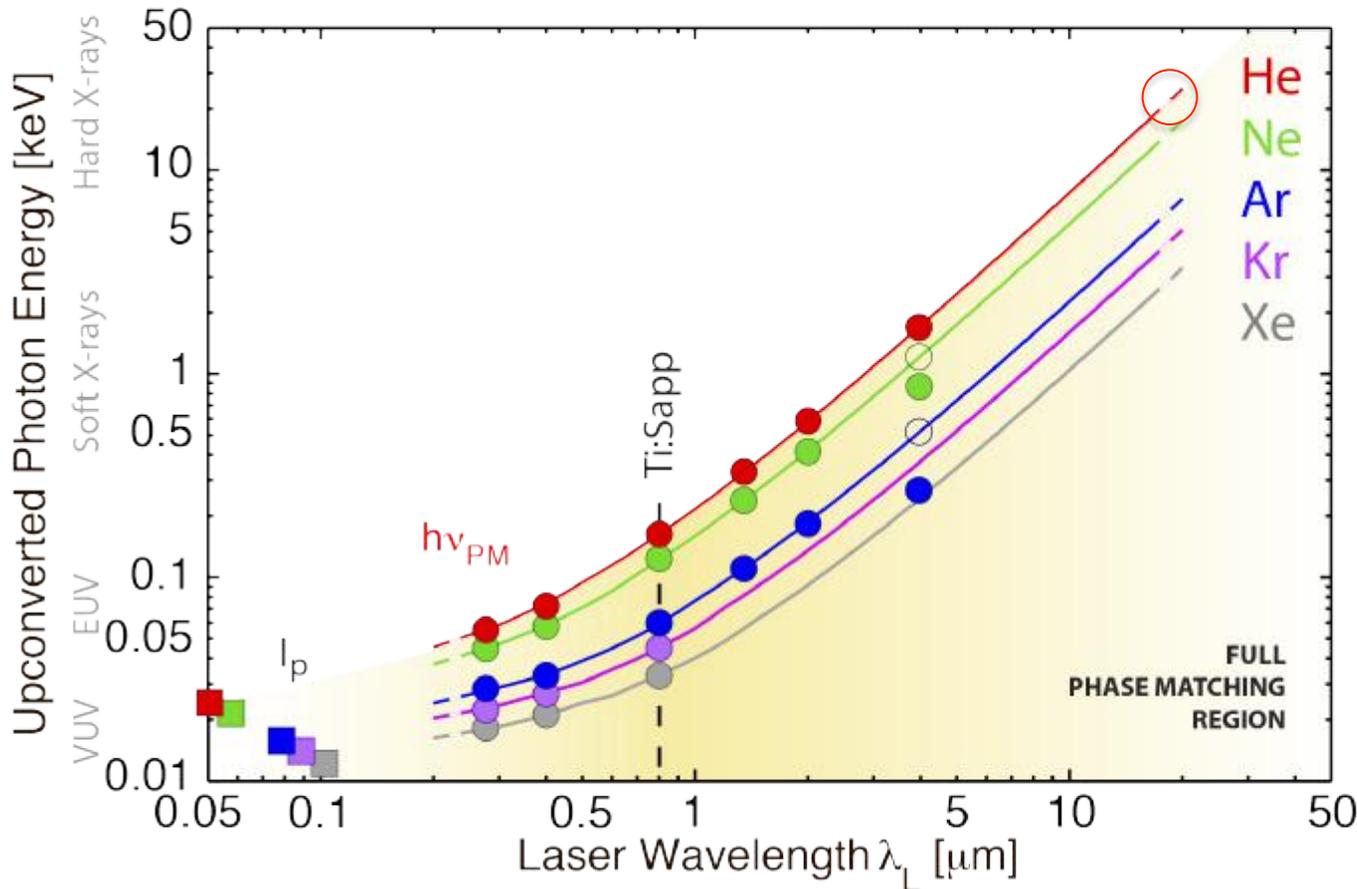
PRX **2**, 011005 (2012)
 PNAS, **109**, 4792 (2012)
 Nature Commun. **3**, 1037 (2012)

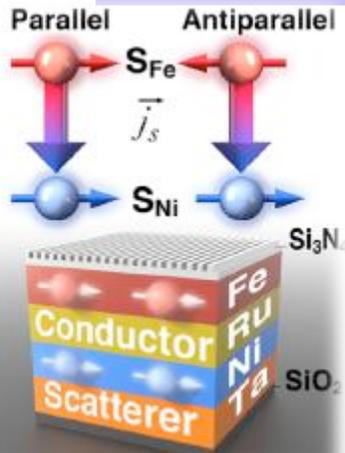
NEWS ARTICLES ABOUT WORK

Physics **5**, 11 (2012)
 Physics Today **65** (5), 18 (2012)
 Physik Journal **11**, Nr. 6, page 26 (2012)

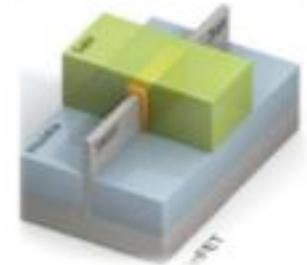
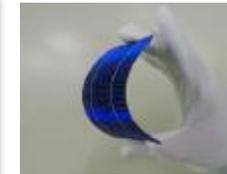
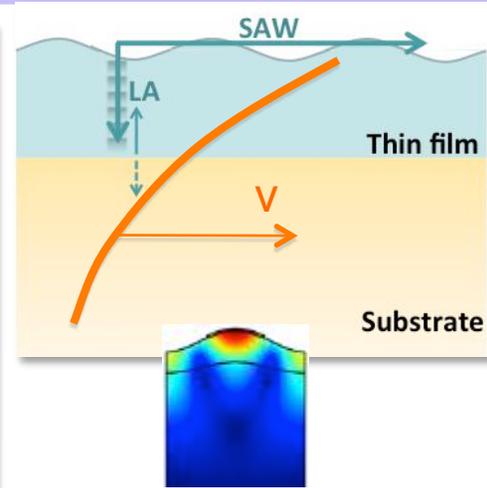
- 20 μm mid-IR lasers may generate bright 25 keV beams
- $\approx 1/2$ million order phase-matched nonlinear process!

Phase Matching Cutoffs
VUV-EUV-Soft & Hard X-rays

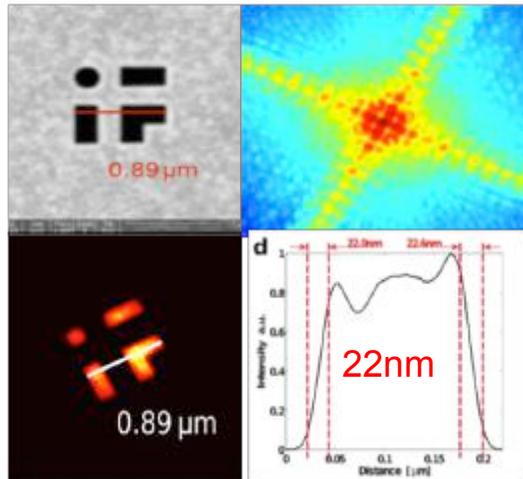
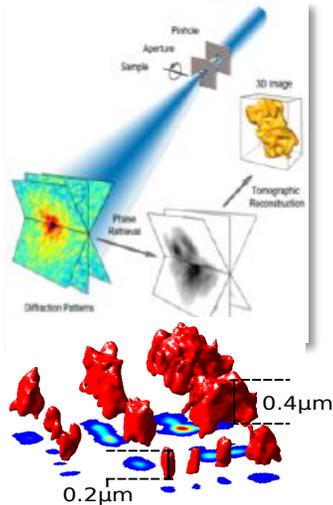




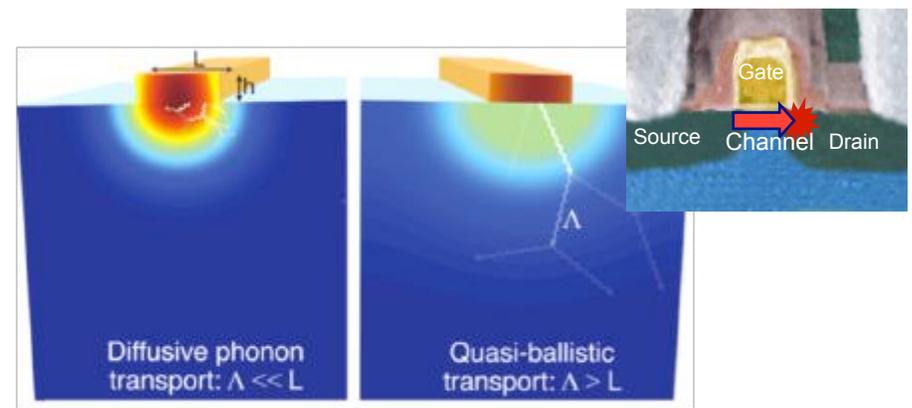
Ultrafast elemental-specific spintronics: (*Nature* **471**, 490 (2011), *PNAS* **109**, 4792 (2012); *Nature Comm* **3**, 1037 (2012); *Nature Comm* **3**, 1069 (2012))



Acoustic nanometrology: thin film metrology (*Nano Letters* **11**, 4126 (2011); *SPIE, PRB* (2012))

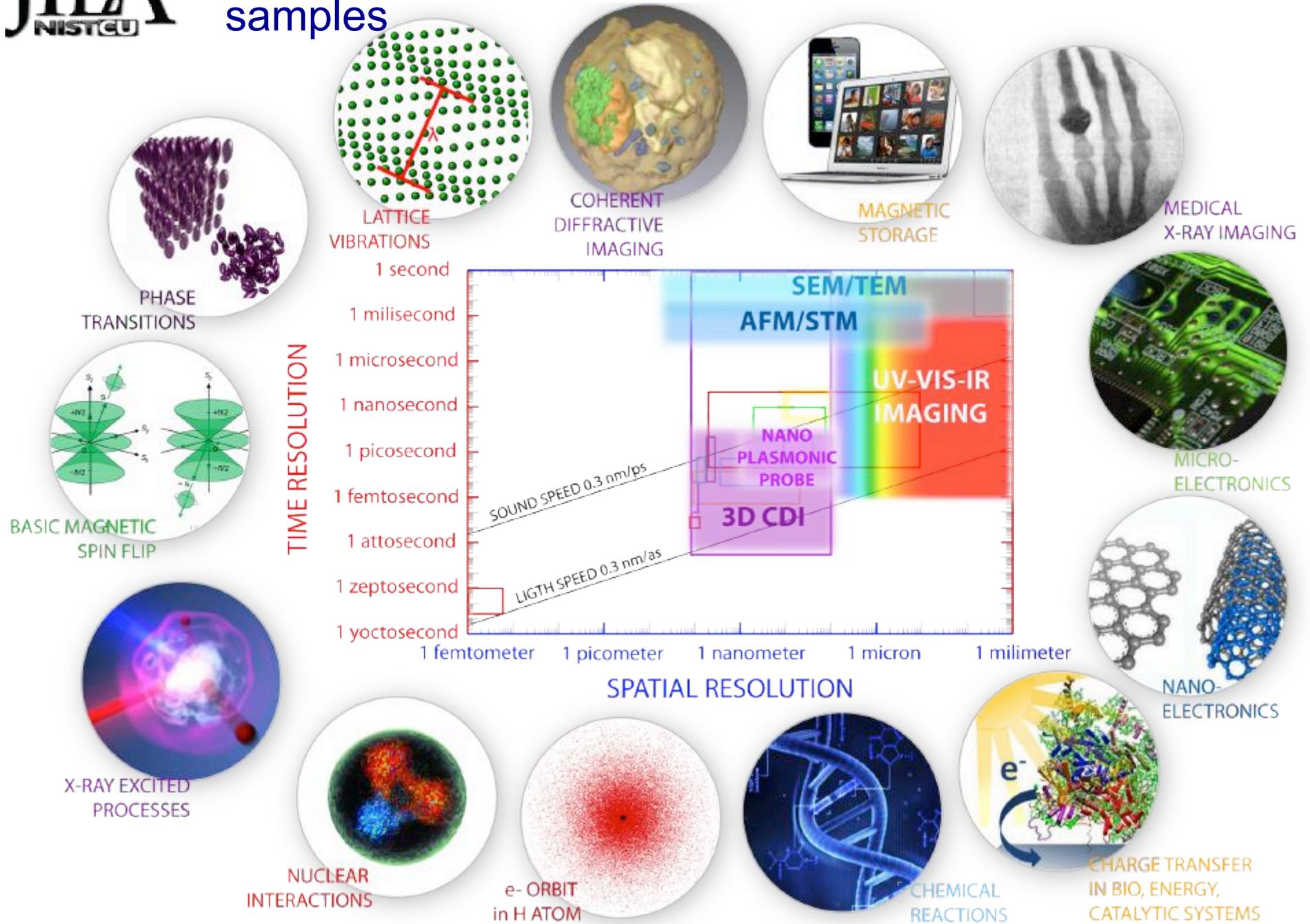


Nanoscale imaging: Record tabletop 22nm resolution (*Op. Ex.* **19**, 22470 ('11); **17**, 19050 ('12); *Nature* **463**, 214 (2010))



Nanoscale energy transport: probe nanoscale energy/strain flow (*Nature Materials* **9**, 26 (2010); *Nano Letters* **11**, 4126 (2011); *PRB* **85**, 195431 (2012))

HHG – unique probe of nanoscale function in thick samples





Chan La-O-Vorakiat
(Singapore)



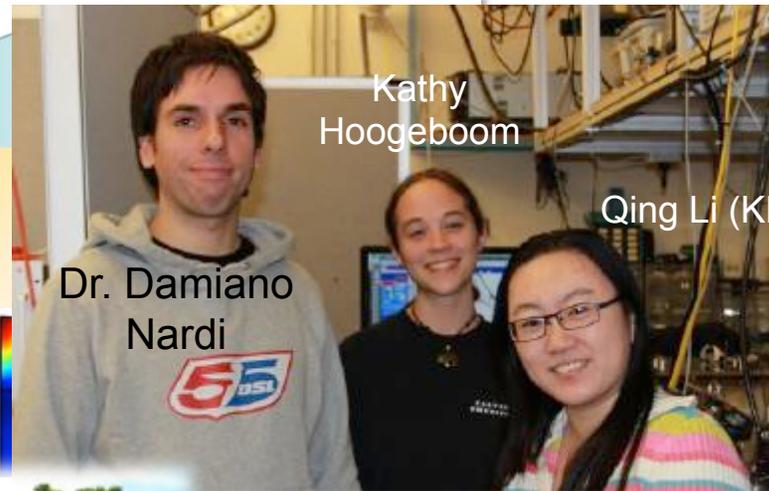
Emrah
Turgut



Dr. Stefan
Mathias



Patrik
Grychtol

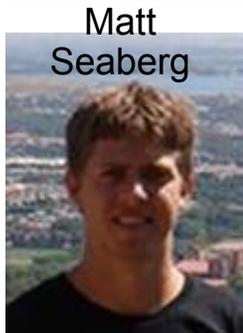


Dr. Damiano
Nardi

Kathy
Hoogeboom

Qing Li (KLA)

Magnetic and material switching speeds, spin transport



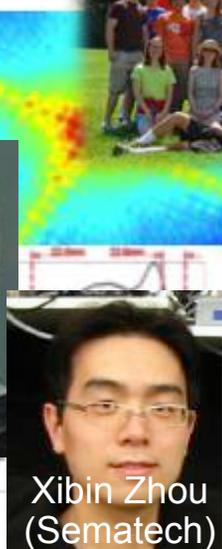
Matt
Seaberg



Dennis
Gardener



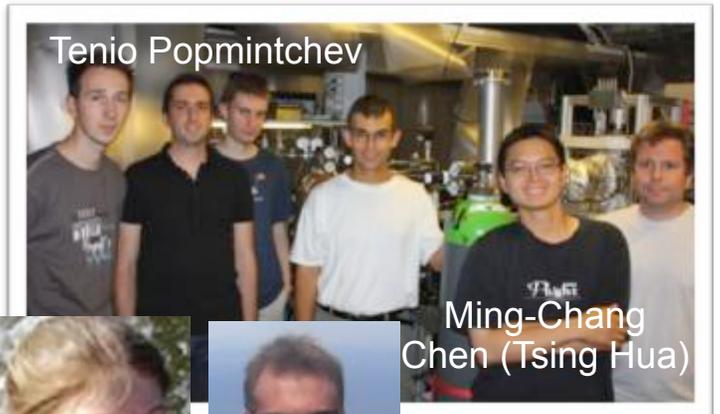
Bosheng
Zhang



Xibin Zhou
(Sematech)



Nanoscale acoustic metrology and energy transport

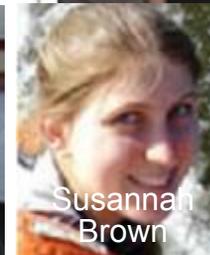


Tenio Popmintchev

Ming-Chang
Chen (Tsing Hua)



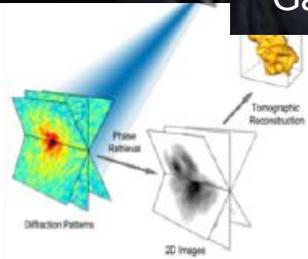
Dimitar
Popmintchev



Susannah
Brown



Michael
Gerrity



Nanoscale imaging

High harmonic sources